



2024年第四届半导体辐射探测器研讨会 @ 青岛

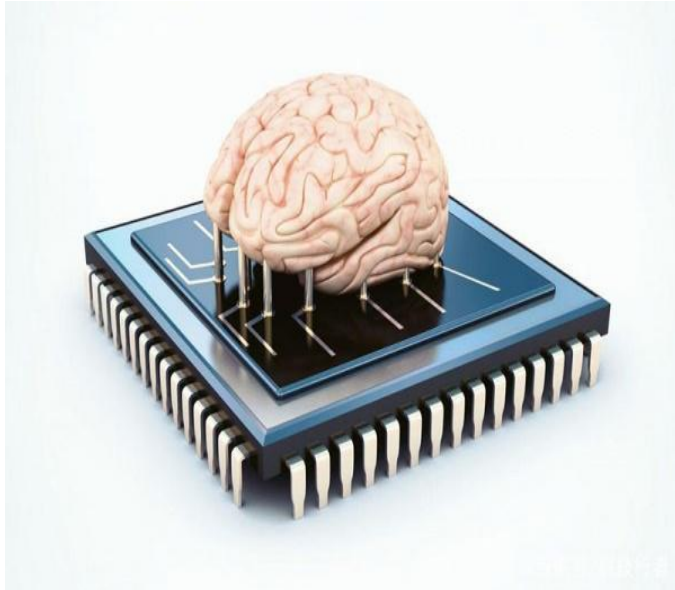
# 半导体辐射探测器前端读出电子学前沿技术及发展趋势

Frontier Technologies and Trends of Front-end Readout Electronics for  
Semiconductor Radiation Detectors

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- 1 Research Background**
- 2 Front-End Readout ASICs**
- 3 Intelligent Front-end Processors**
- 4 R&D Progress of Our Group**
- 5 Conclusion and Perspective**

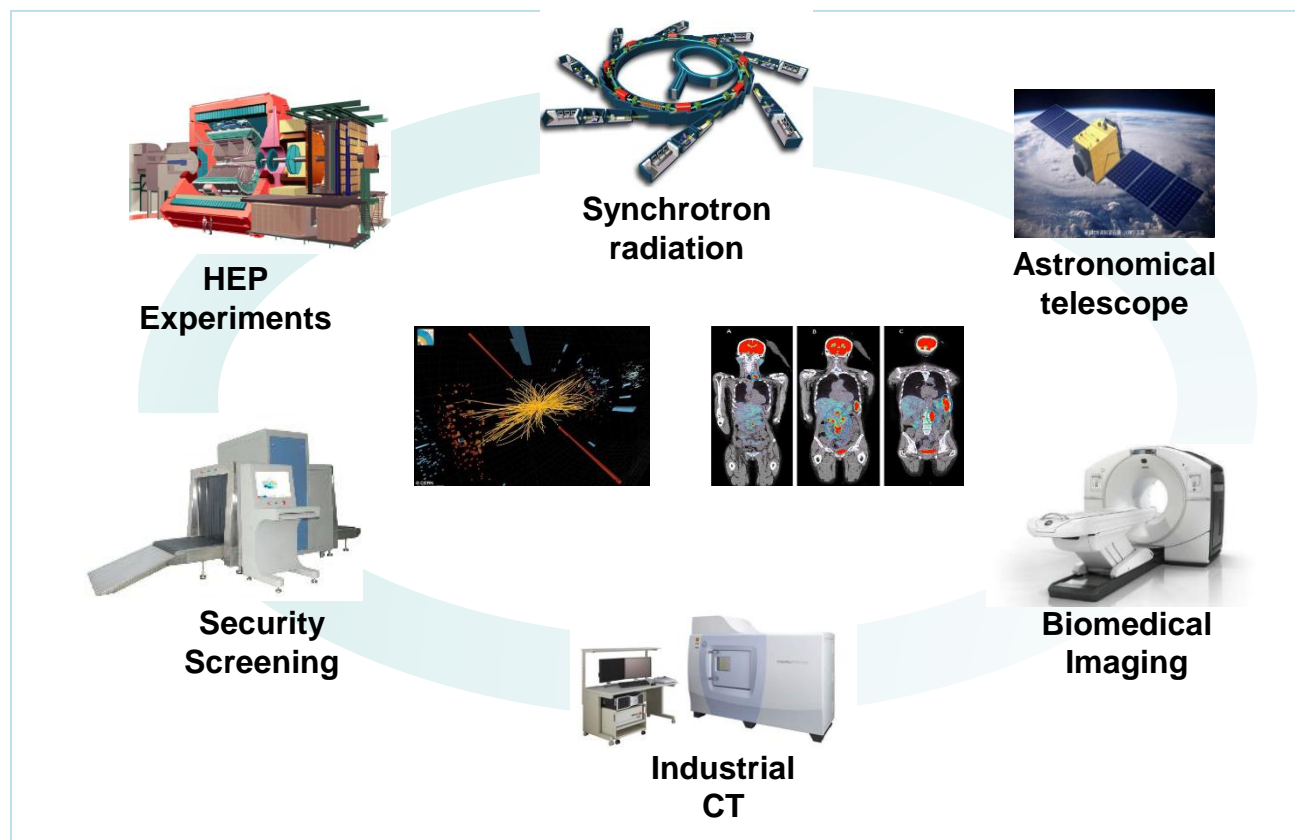
# Research Background

# 1 Semiconductor Radiation Detectors

## □ “Eyes” of Radiation Instrumentation

- Charged particles ( $h^+$ ,  $e^-$ ,  $\alpha$ ,  $\beta$ , Heavy ions), neutrons, photons (X,  $\gamma$ -rays)
- Features  $\rightarrow$  Continuous pulse signals, random in time and amplitude

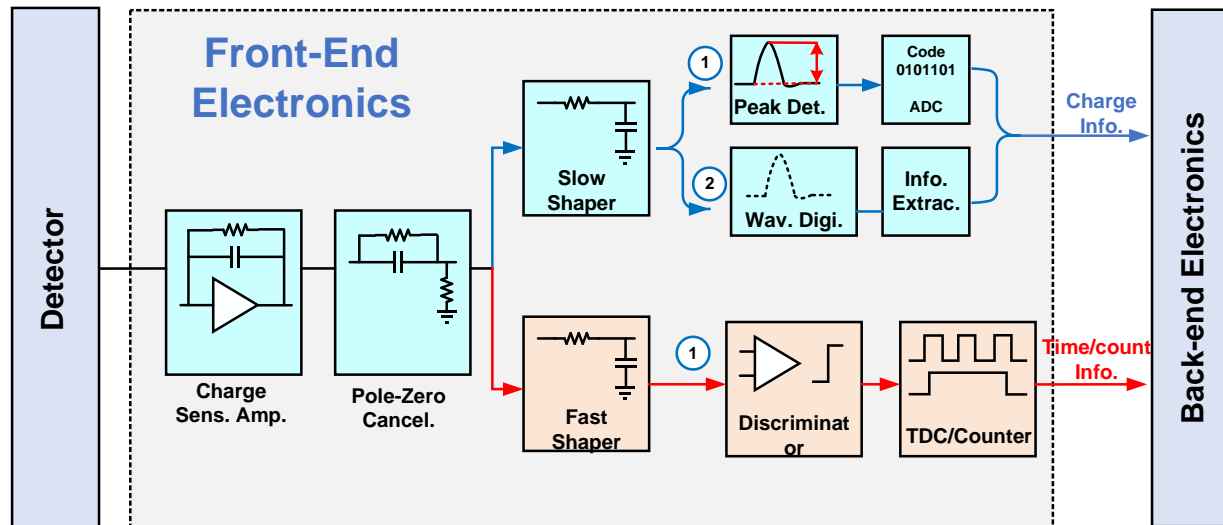
$$Q_E = \frac{E_{dep}}{\epsilon_x} = \frac{E_1 - E_2}{\epsilon_x} \propto \Delta V_{step}$$



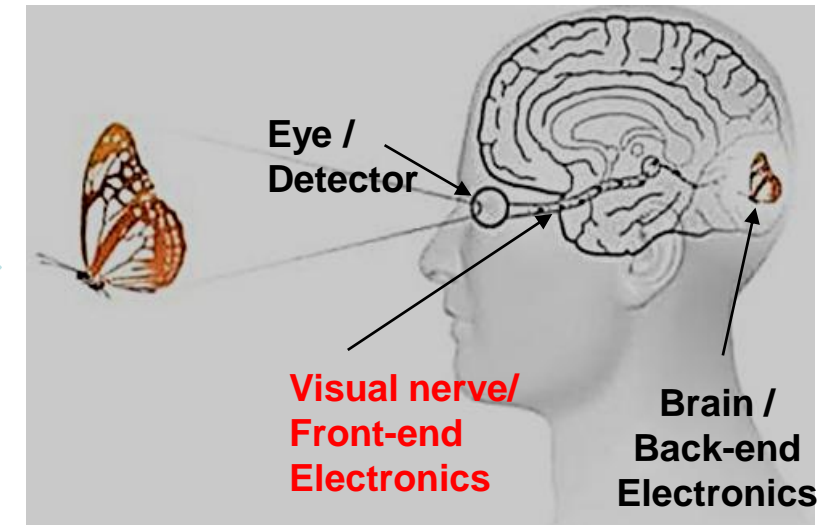
# 1 Front-End Electronics

## □ Discrete Circuits & Application-Specific Integrated Circuits (ASICs)

- **Signal Modulation:** Readout, Charge & Time Measurement, Photon counting
- **Digitization:** for future processing by computers
- Performance **bottle-neck** of the detector system



(After L. Zhao, 2023)

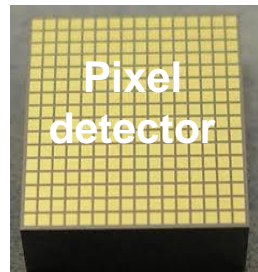


**Common solution and frontier technologies →**  
**Employing ASICs to construct front-end electronics**

# 1 Physical Implementation

## □ Multichannel Readout ASICs

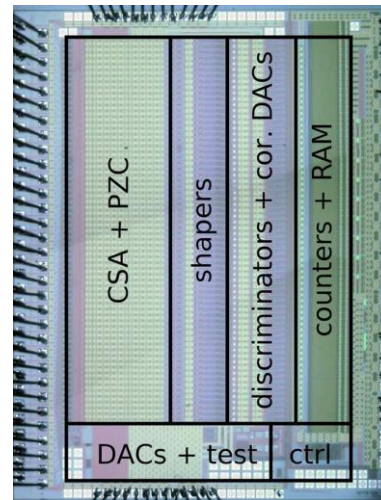
- **Main Blocks:** Charge-Sensitive Amplifier, Pulse Shaper, Discriminator, Peak Detector, ADC/TDC, Counter, Shift Registers
- **Feature:** “Big **A**nalog, Small **D**igital” (大A小D)



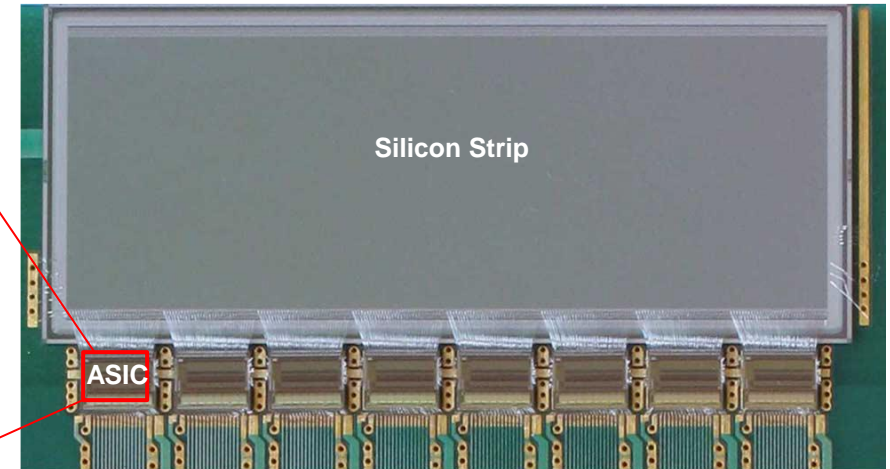
Pixel detector



Multichannel electronics



Strip ASIC (64/128/160)



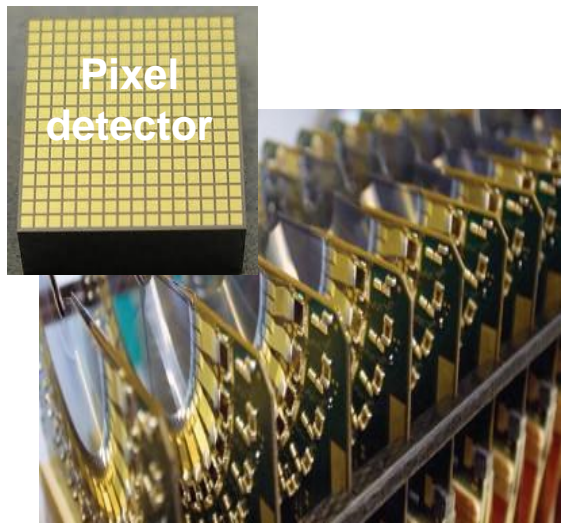
Si Strip Detector module

(R. Szczygiel, AGH Univ. of S&T, Poland, TNS, 2009)

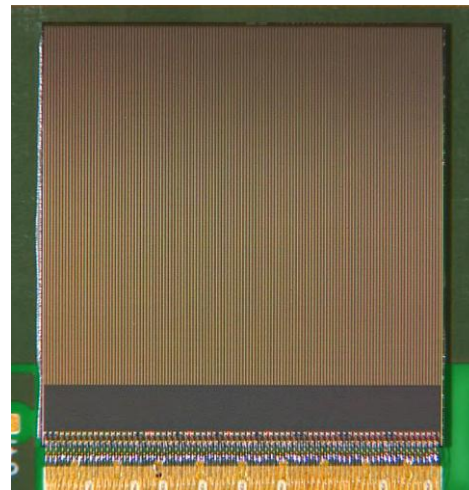
# 1 Physical Implementation

## □ Pixel Readout ASICs

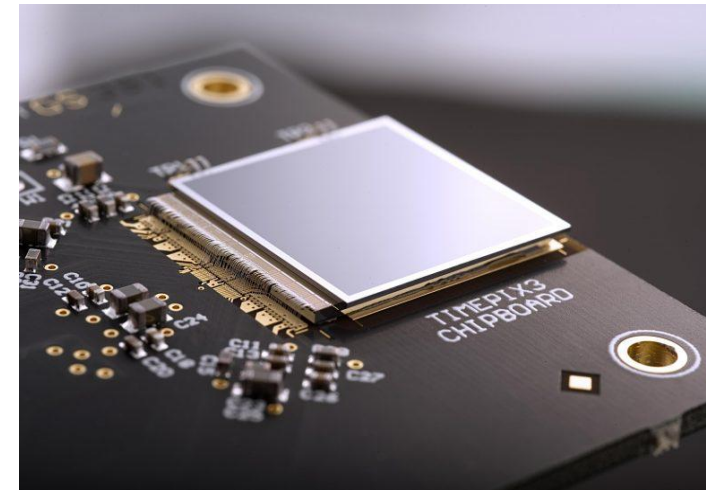
- **Main blocks:** Pixel AFE, Pixel ADC/Counter, Readout Matrix, PISO Registers, Serializer, PLL and Global Controller
- **Feature:** “**A**nalog Islands in **D**igital Sea” (数字海、模拟岛)



Multichannel electronics



Pixel ASIC (50μm pitch,  
256×256)



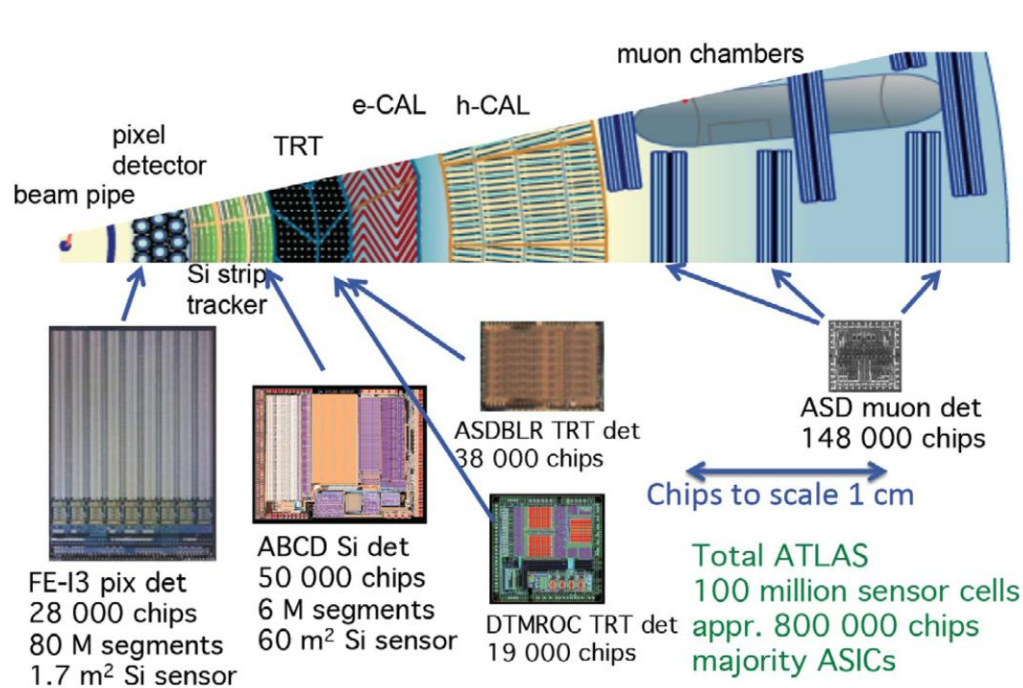
Hybrid Pixel Detector

(<https://home.cern/>)

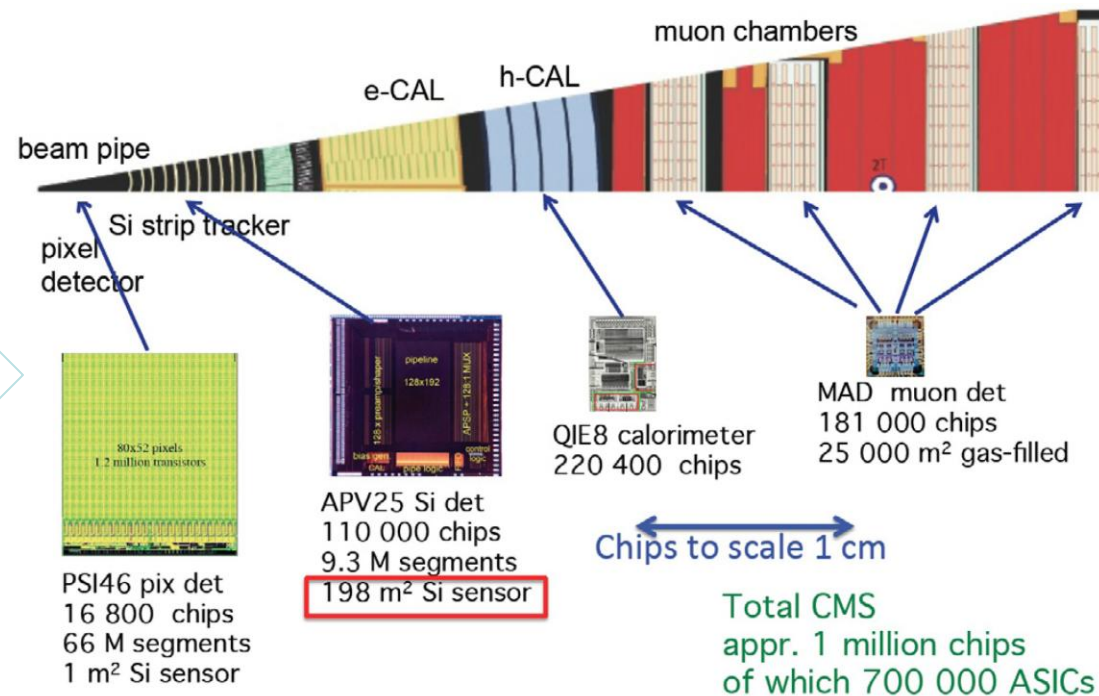
# 1 Application Example

## ASiCs for High-Energy Physics Collider

- Illustrate the radial positions of different systems in the LHC ATLAS/CMS
- Different types, Different performance, the amount of chip **up to 0.8 million**



ATLAS detector



CMS detector





# 1 R&D Challenges

## □ Complex Design Considerations

### – Performance Matching

- Dynamic Range
- Noise Performance
- Linearity
- Shaping Time/Count Rate
- ADC resolution
- Time precision
- Consistency
- Power dissipation

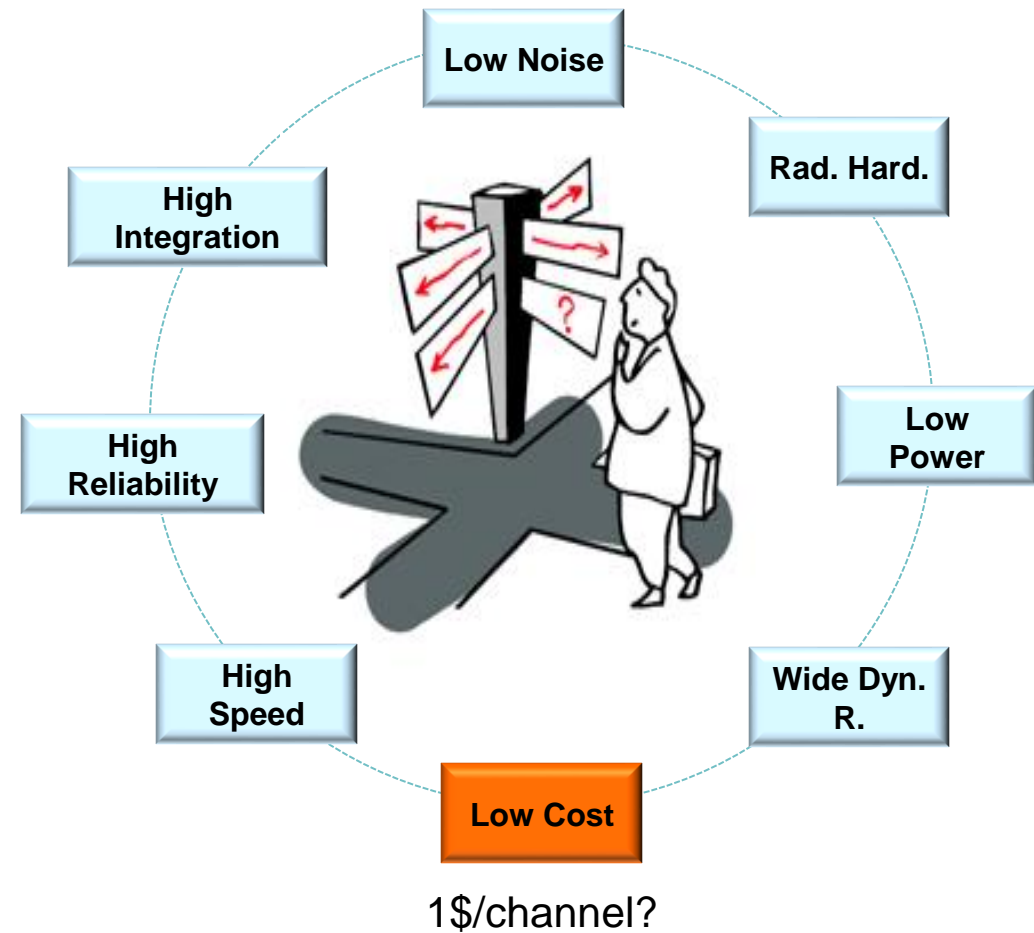
### – Physical Connection

- Package/COB/flip chip/TSV

### – Reliability

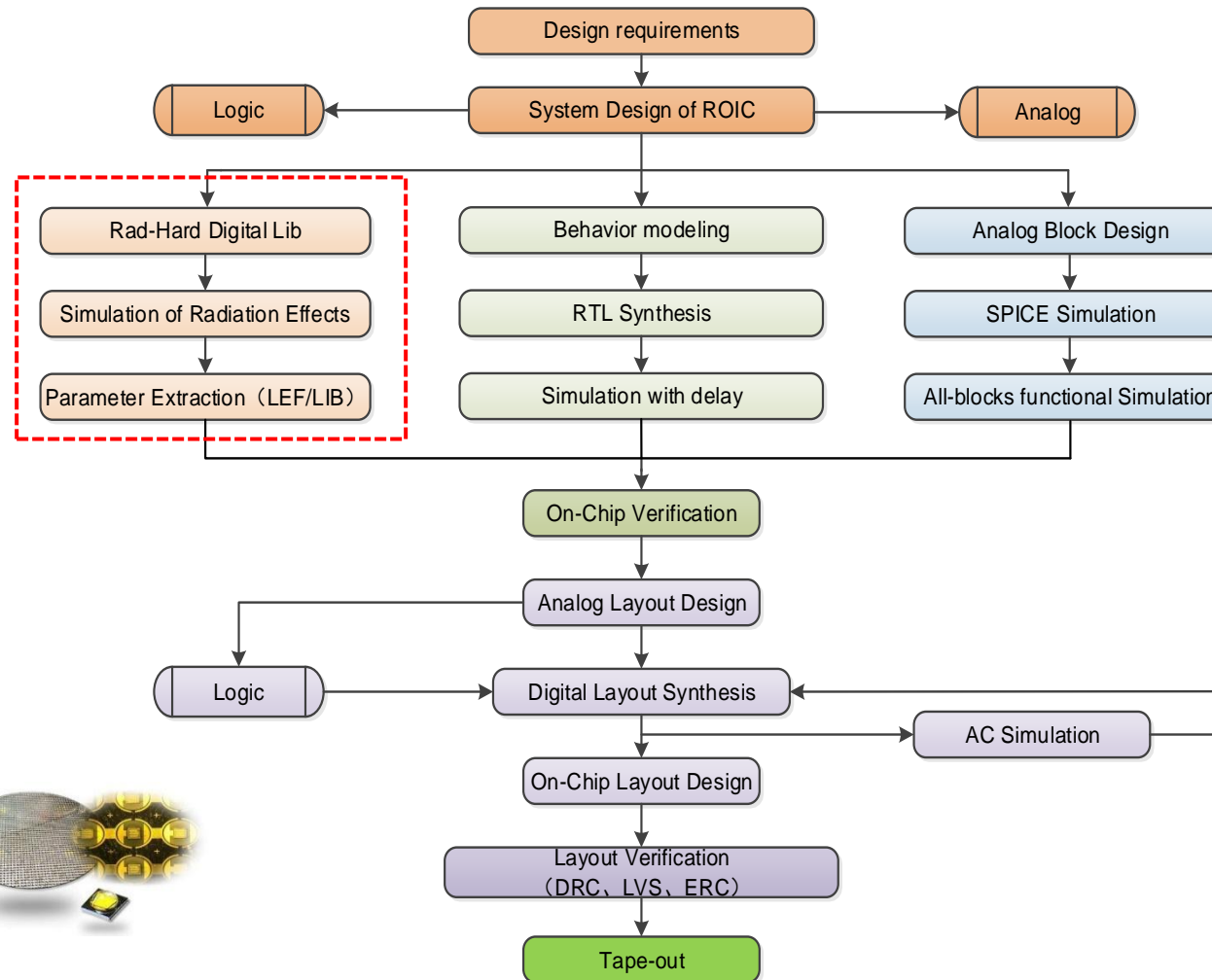
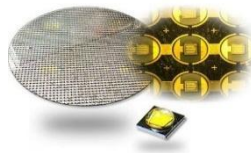
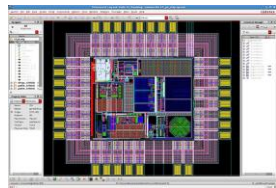
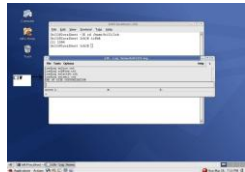
- Rad. Hard., Low temp., Life

### – Yield & Cost



# 1 R&D Challenges

Multiple iterations → 4~6 years/product



System Design  
1~2 months

Circuit Design  
3~4 months

Layout Design  
3~4 months

Fabrication & Testing  
2~3 months

# Front-End Readout ASICs: A Survey

# 2 Research Institutions

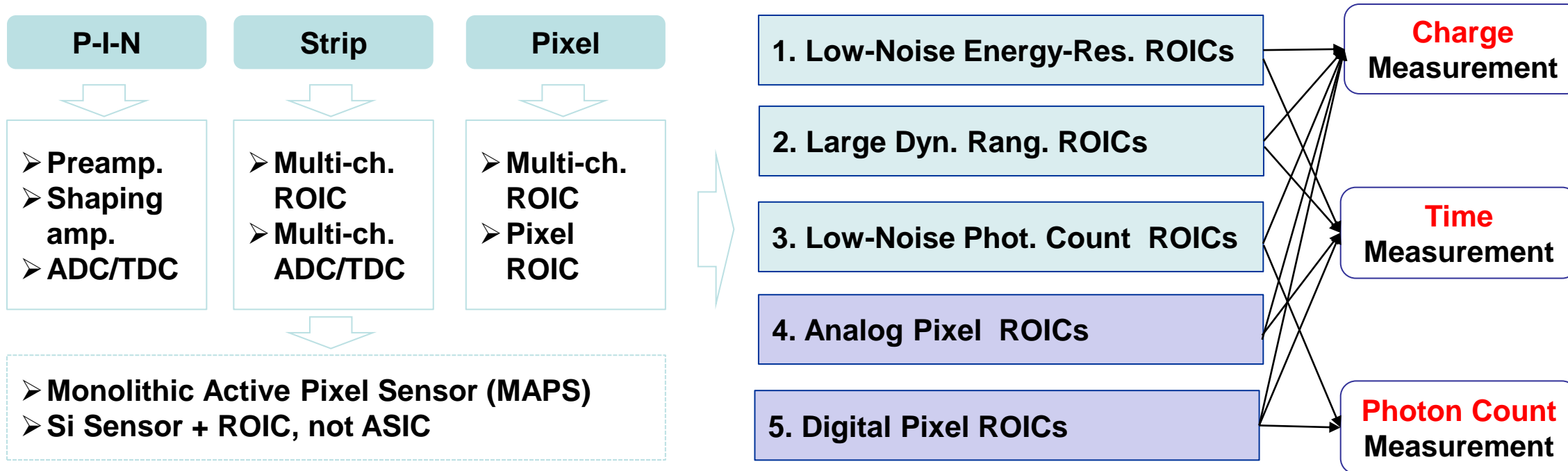
## □ Distribution of ASIC Designers



Source: ASICs in published papers and books during 2000-2023

# 2 Classification

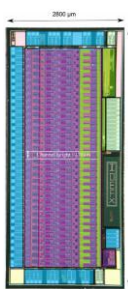
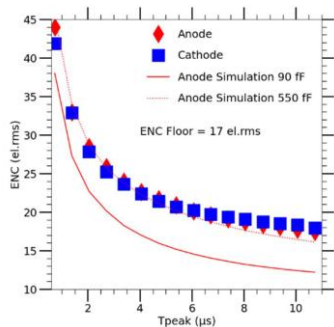
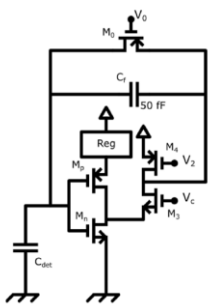
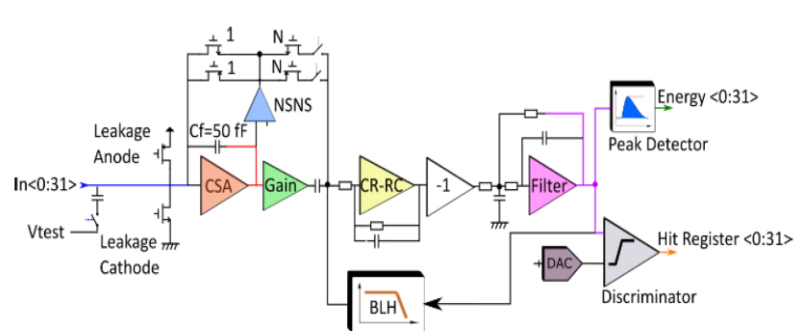
## Development of Front-End ASICs in the last 20 years



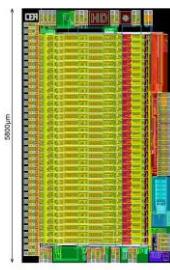
# 2 State-of-the-art Work

## □ Type I: Low-Noise Energy-Resolving ROICs

- Topology: CSA, PZC, CR-RC<sup>n</sup>, PDH, BLH, DSC, DAC, Mux, TCON
- **IDeF-X**: 0.35 μm, 32 ch, ±40 fC, **17 e<sup>-</sup>**, 0.73 μs <τ<sub>p</sub>< 10 μs, 100 kcps, **0.85 mW/ch**
- Low-level threshold is ~ **1.2 keV @ Si Drift Detector, X-ray tube, -10 °C**



IDeF-X ECLAIRS, 2009



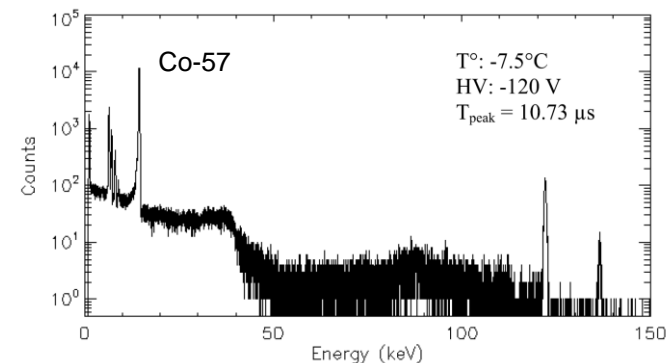
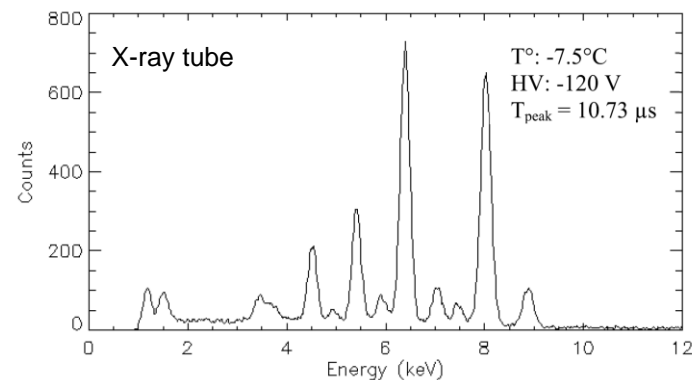
IDeF-X HD, 2010



IDeF-X BD, 2015



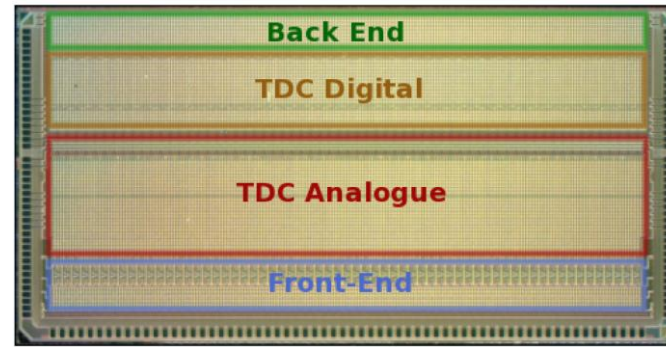
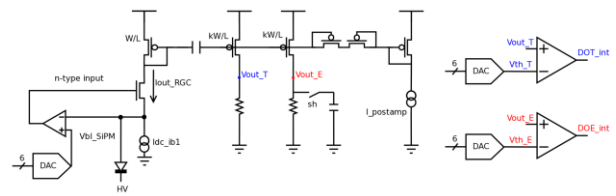
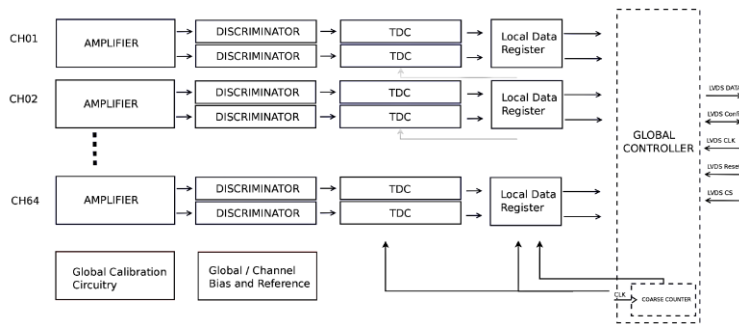
IDeF-X HDBD, 2022



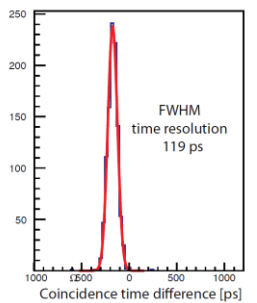
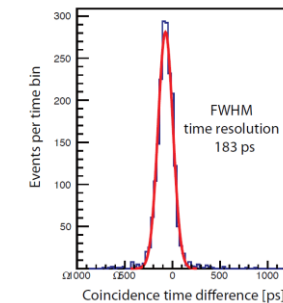
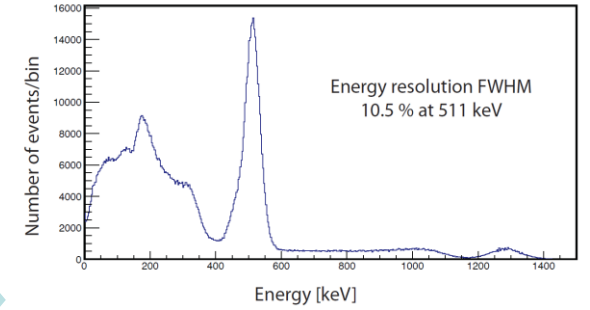
# 2 State-of-the-art Work

## □ Type II: Large-Dynamic Range ROICs

- Topology: TIA, 2 DSC, TDC/TOT, Loc. Reg., Glob. TCON, LVDS
- **TOFPET2**: 110 nm CMOS, **64 ch**, **1500 pC**, 500 kcps, 10b ADC, 30-ps TDC, 3.2 Gbps, 8.2 mW/ch
- **LYSO/SiPM** → 10.5 % @ 511 keV Na-22, Coin. Time Res. 119 ps



(M. D. Rolo, IFEP, Lispoa, Protigal, Jinst, 2013)





# 2 State-of-the-art Work

## □ Type III: Low-Noise High-Rate Photon-Count ROICs

- Topology: CSA, PZC, CR-RC<sup>n</sup>, 8 DSC, 8 Counters, Readout, LVDS
- 180 nm CMOS, **160 ch**, 214 e<sup>-</sup>, 10 ns <math>\tau\_p</math> < 40 ns, **17 Mcps**, 4.2 mW/ch → **8 energy bin** with 8b counters for strip detector

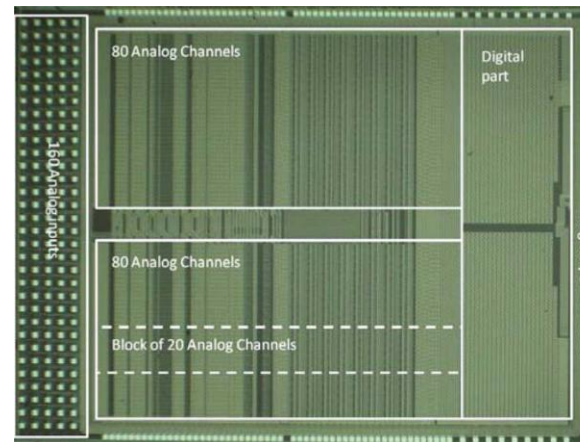
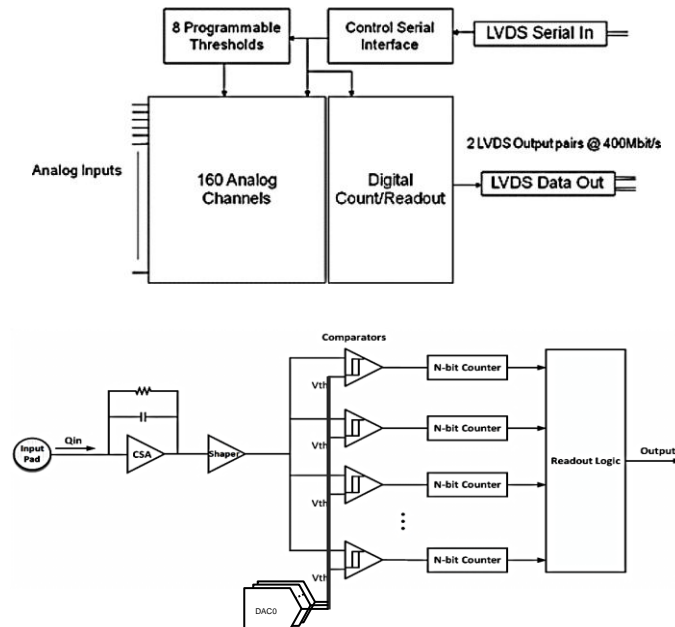


TABLE II  
ASIC OVERVIEW

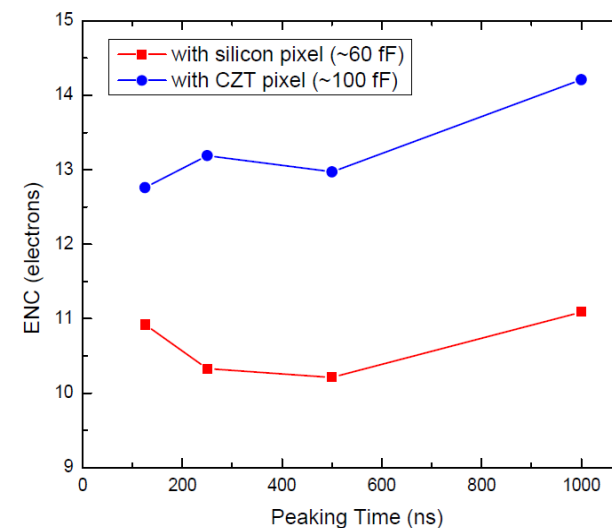
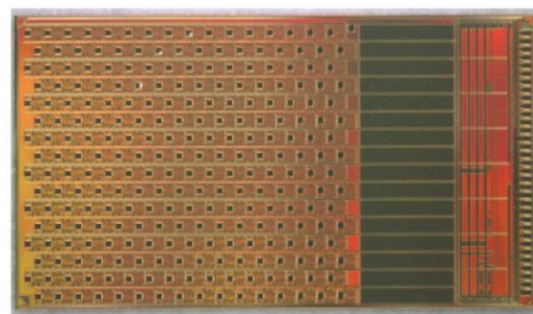
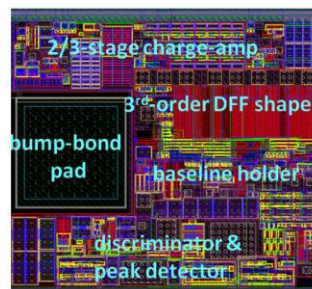
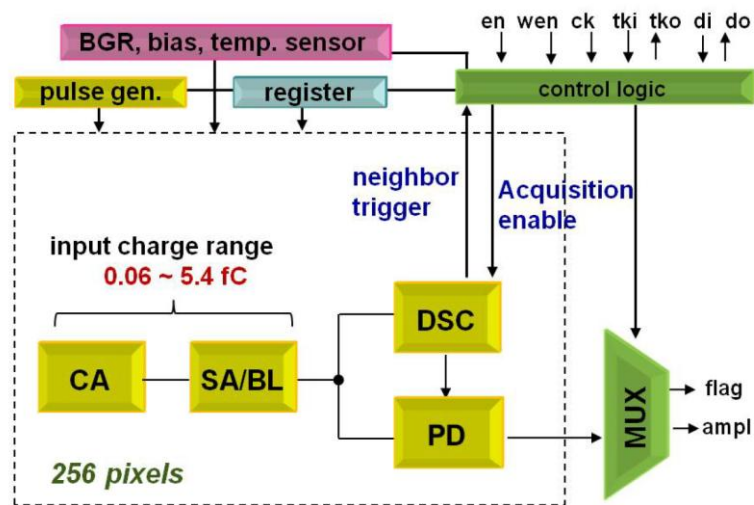
	Target/Simulation	Measured
Number of channels	160	
Gain	2.08mV/keV	2.10mV/keV
Noise level, ENC	300 electrons @5pF	214 electrons @~5pF
Number of energy bins	8	
Counter resolution	8b	
Peak times	10ns, 20ns, 40ns	10ns, 20ns, 40ns
Maximum count rate	17Mcps @100MHz	17Mcps@100MHz
Maximum frame rate	37kframe/s @100MHz	
Process	180nm CMOS	180nm CMOS
Clock frequency	100MHz, 200MHz	100MHz
Power consumption	800mW @200MHz	670mW @100MHz
Chip area	5mm x 6.6mm	

(M. Gustavsson, Linköping University, Sweden, TNS, 2012)

# 2 State-of-the-art Work

## □ Type IV: Analog Pixel ROICs

- Topology: Pixel AFE(CSA+SP+BL+DSC+PDH) , Mux, Reg., Global TCON, BGR, Bias, Temp. Sensor
- **HEXID2**: 130nm CMOS,  $250 \times 250 \mu\text{m}^2$ ,  $16 \times 16$ ,  $0.06 \sim 5.4 \text{ fC}$ ,  $10 \sim 15 e^-$ ,  $0.125 \mu\text{s} < \tau_p < 1 \mu\text{s}$ ,  $0.6 \text{ mW/pix} \rightarrow \text{Si/CZT pixel detector for space X-ray imaging}$

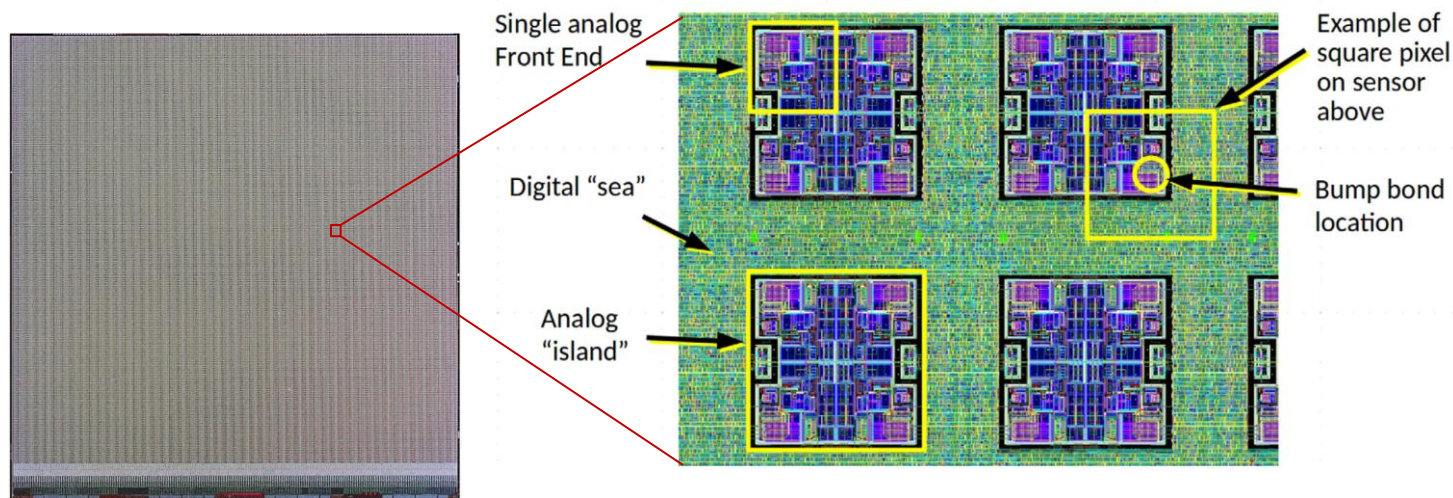
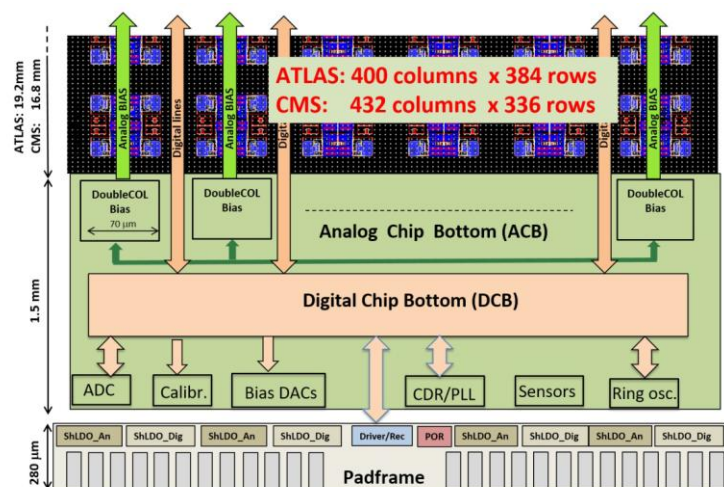


(S. Li, BNL, USA, 2017)

# 2 State-of-the-art Work

## □ Type V: Digital Pixel ROICs

- Topology: Pixel AFE(CSA+SP+BL+DSC), Pixel ADC/Counter, Readout Matrix, PISO Registers, Serializer, PLL and Global Controller
- **RD53C**: 65 nm CMOS,  $50 \times 50 \mu\text{m}^2$ ,  $400 \times 384$ ,  $\pm 40 \text{ fC}$ ,  $600 \text{ e}^-$ ,  $3 \text{ GHz/cm}^2$ ,  $10 \mu\text{W/pixel}$ , 500 Mrad
- Others: FE-I4, TDCPix, Velopix, Medipix4, Timepix4, MPA, ClicPix

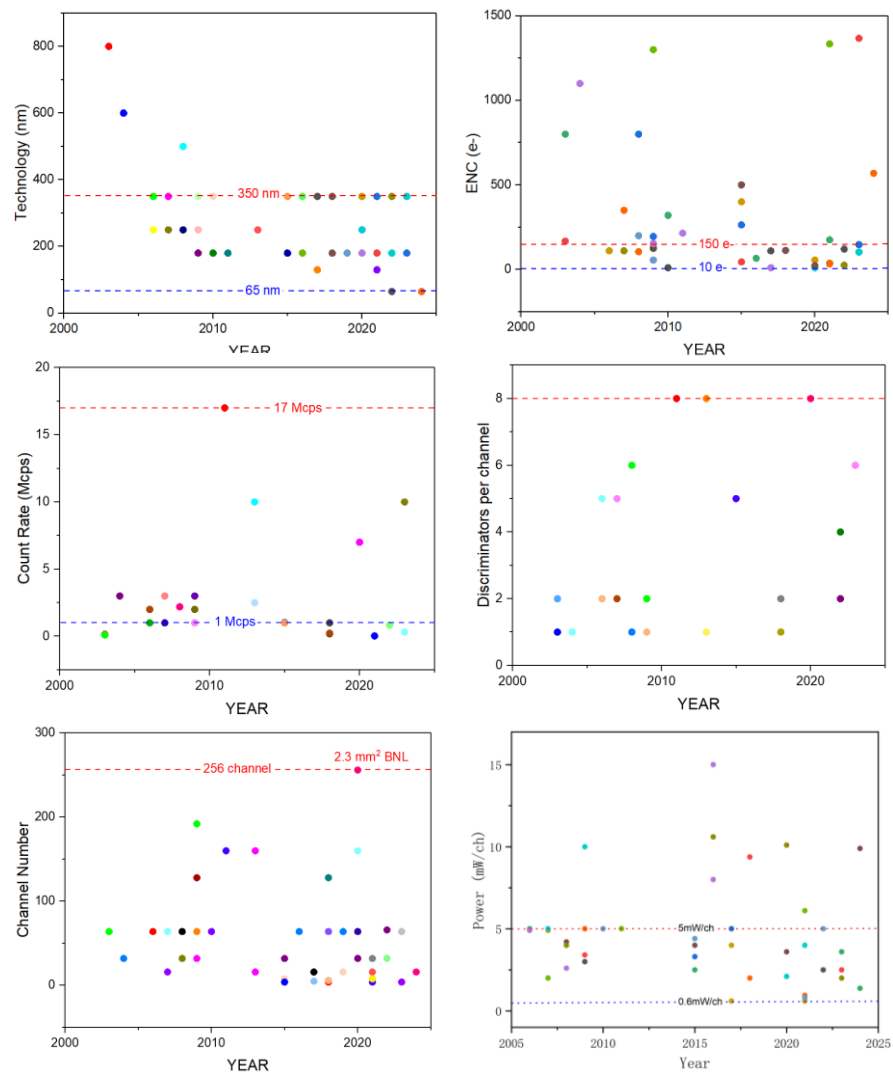


(G.-S., Maurice, LBNL, USA, 2024)

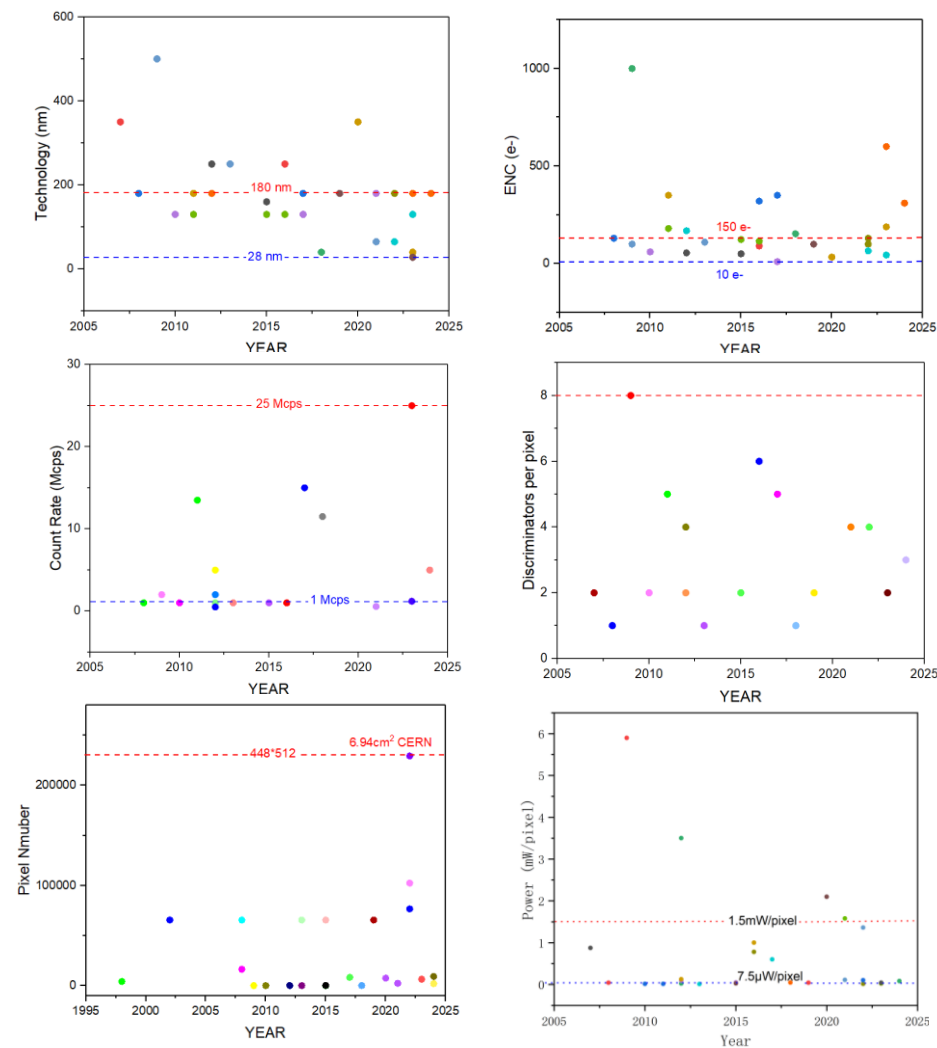
# 2 Performance Overview



## Multichannel ROICs



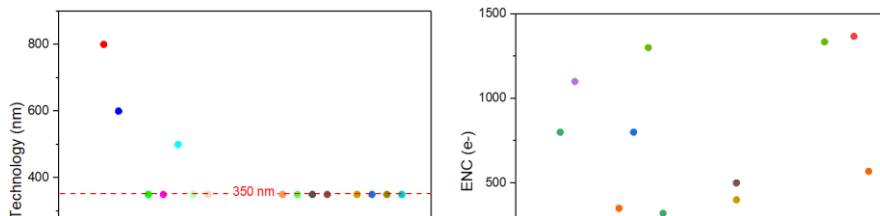
## Pixel ROICs



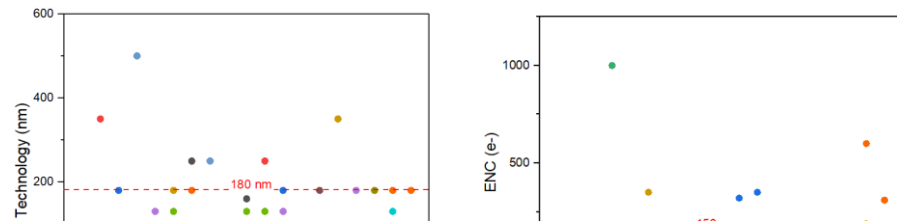
(Source: ASICs in published papers and books during 2000-2023)

# 2 Performance Overview

## Multichannel ROICs



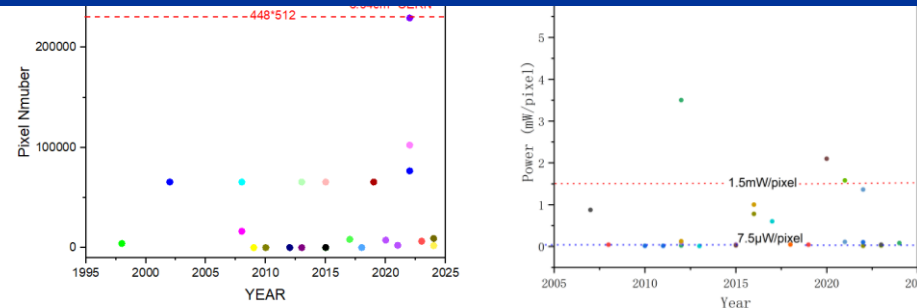
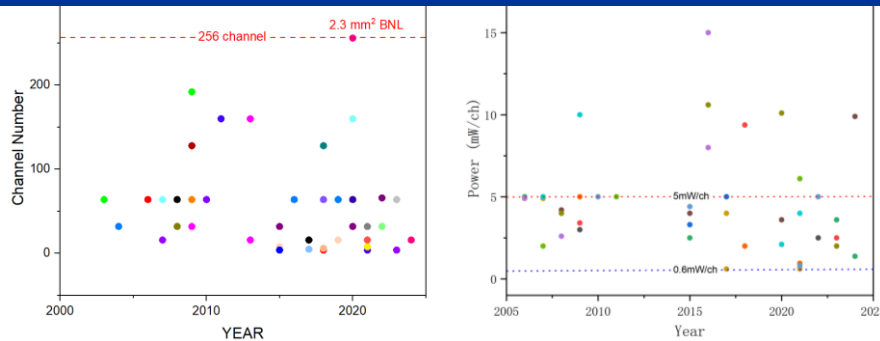
## Pixel ROICs



## Conclusion

### □ Main Electrical Characteristics

- Fabrication Process (nm) : 350 → 250 → 180 → 130 → 65 → 40 → 28 (Adv. 65 Vs. 28)
- Equivalent Noise Charge (e-) : < 150 (Mini. ENC 10 Vs. 10)
- Count Rate (Mcps): 0.5 → 1 → 2 → 3 → 5 → 10 → 17 → 25 (Max. 17 Vs. 25)
- Discriminators per channel/pixel: 1 → 2 → 4 → 5 → 6 → 8 (Max. 8 Vs. 8)
- Channel/Pixel Number: Continuously increasing (Max. 256 Vs. 448×512)
- Power Dissipation (μW/ch) : 7.5 ~ 5000 (Mini. 600 Vs. 7.5)

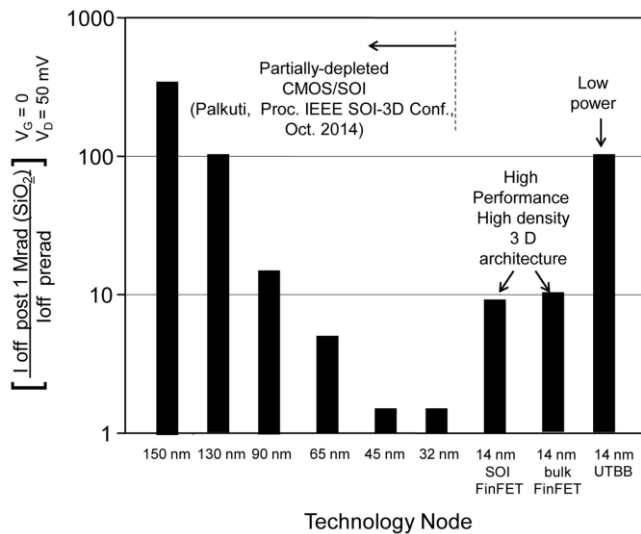


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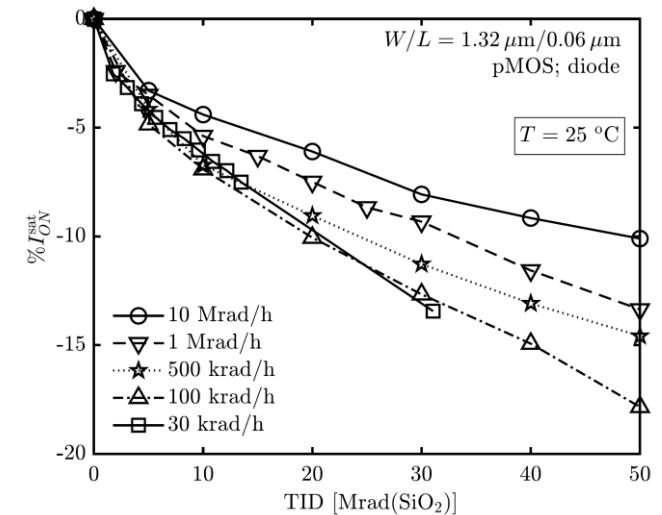
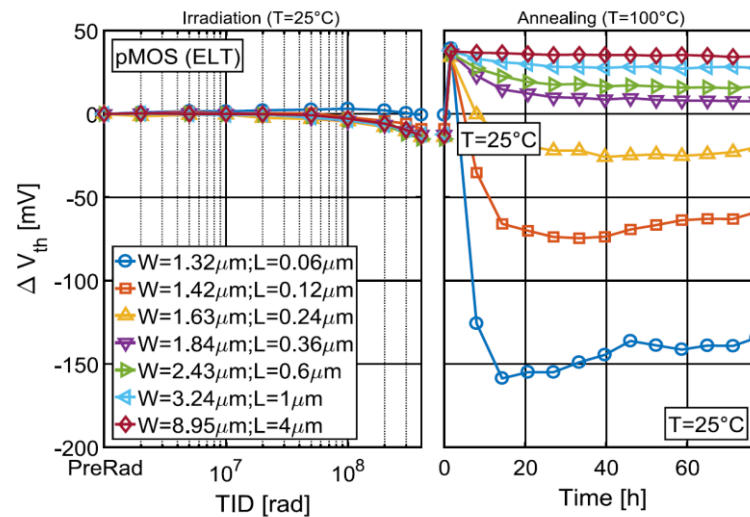
# 2 Performance Overview

## □ Total ionization dose (TID)

- $I_{D,off}$  reduced with the shrink of process nodes, but worse for 14-nm FinFETs
- **65 nm CMOS**: ELT shown tiny  $I_{D,off}$  and  $\Delta V_{th}$ , @ **100 Mrad** but  $I_{D,sat,on}$  affected by dose rate effects
- **Medipix/Timepix Family** → **800 Mrad**



(Hughes,2015)

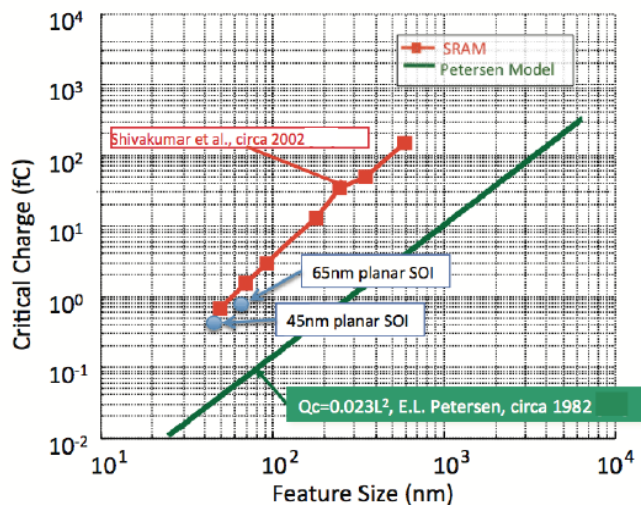


(F. Faccio, CERN, NIM A, 2023)

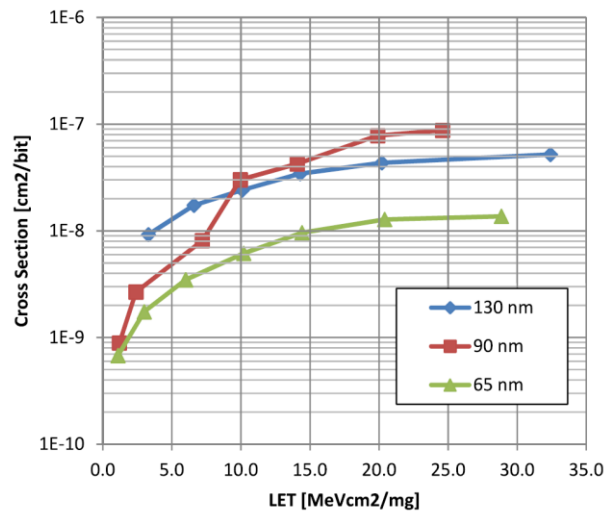
# 2 Performance Overview

## □ Single Event Effects (SEE)

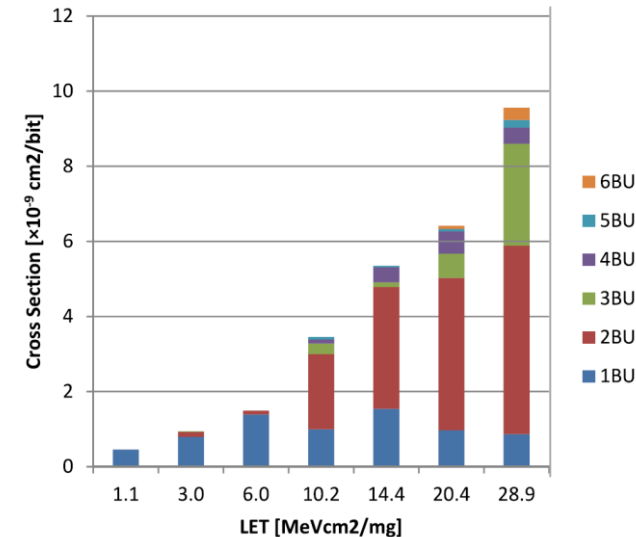
- Critical charge < 1 fC @ sub-100 nm nodes → lower  $LET_{th}$  → **Multi-bit upset (MBU)**
- Triple-Mode Redundancy, Time Redundancy, EDAC →  $LET_{th} > 75 \text{ MeVcm}^2/\text{mg}$
- SEL immunity →  $LET_{th} > 100 \text{ MeVcm}^2/\text{mg}$



( Massengill, 2012 )



( F. Faccio, CERN, NIM A, 2023 )



# 2 Performance Overview

## □ Technical Trends

- Overseas: 28 nm, larger ch./matrix, 10 e<sup>-</sup>(rms), 25 Mcps, ~μW/ch, 800 Mrad
- Domestic: all types involving, less applications

Parameter	Overseas		Domestic	
	Multichannel	Pixel	Multichannel	Pixel
Process (min)	65 nm	<b>28 nm</b>	65 nm	65 nm
Channel No. (max)	256	<b>448×512</b>	64/128	400×512
ENC (min)	<b>10 e<sup>-</sup></b>	<b>10 e<sup>-</sup></b>	25 e <sup>-</sup>	100 e <sup>-</sup>
Discr. No. (max)	8	8	8	3
Count Depth (max)	24 bits	24 bits	16 bits	24 bits
Count R. (max)	17 Mcps	<b>25 Mcps</b>	10 Mcps	5 Mcps
Power Diss. (min)	600 μW/ch	<b>7.5 μW/pixel</b>	600 μW/ch	38.9 μW/pixel
Radiation hardness	TID > <b>800 Mrad(Si)</b> SEU LET <sub>th</sub> > 75 MeVcm <sup>2</sup> /mg SEL LET <sub>th</sub> > 100 MeVcm <sup>2</sup> /mg		TID > 30 Mrad(Si) SEU LET <sub>th</sub> > 75 MeVcm <sup>2</sup> /mg SEL LET <sub>th</sub> > 100 MeVcm <sup>2</sup> /mg	

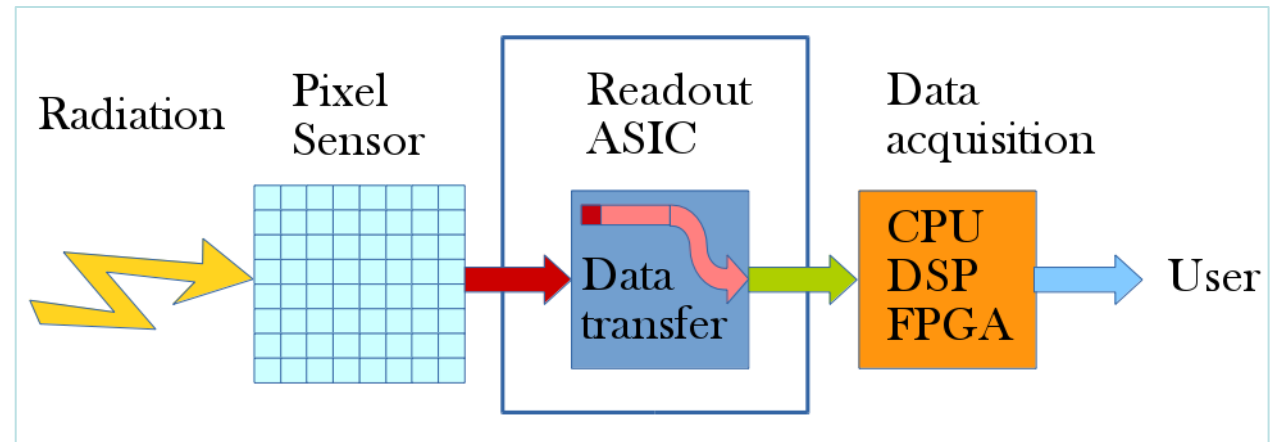
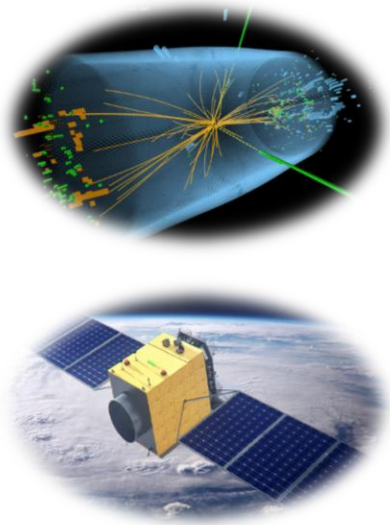


# Intelligent Front-end Processors

# 3 Requirements

## □ Next-generation Instrumentation

- High-luminosity Collider, Energy-resolving photon-counting CT, X-ray Astronomy
- higher precision detectors (**MAPS & HPD**)
- ROIC: 50  $\mu\text{m}$  pitch, 448  $\times$  512 (Timepix4, **200 PB, 4.8 Gbps**)
- New challenges
  - The rapid increasing amount of data
  - Traditional methods are inefficient



# 3 Issues and Solution of Current Electronics

## □ Non-idea effects of Sensing

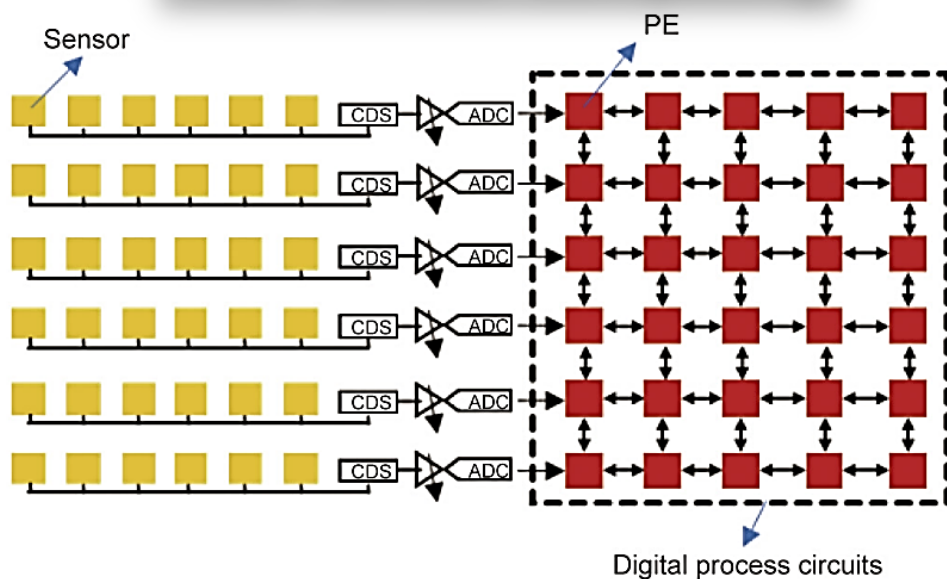
- Compton scattering, charge sharing, piles-up, dark/FPN noise etc.
- Requires feature enhancement

## □ Computation Issues

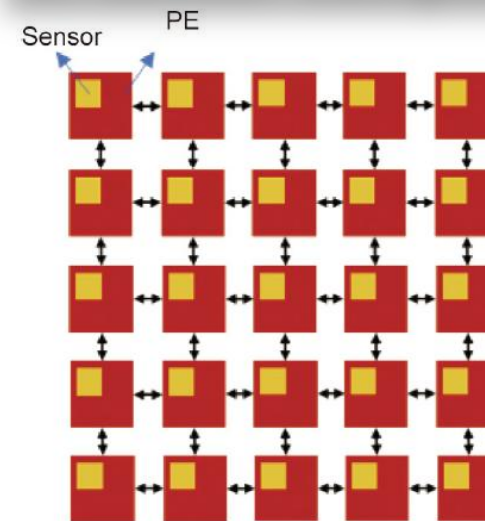
- Increased data stream → Accelerator → Power Wall + Memory Wall
- Requires data compression, feature extraction & recognition

**Fusion of Sensing and computing is a trend**

### Near-Sensor Computing



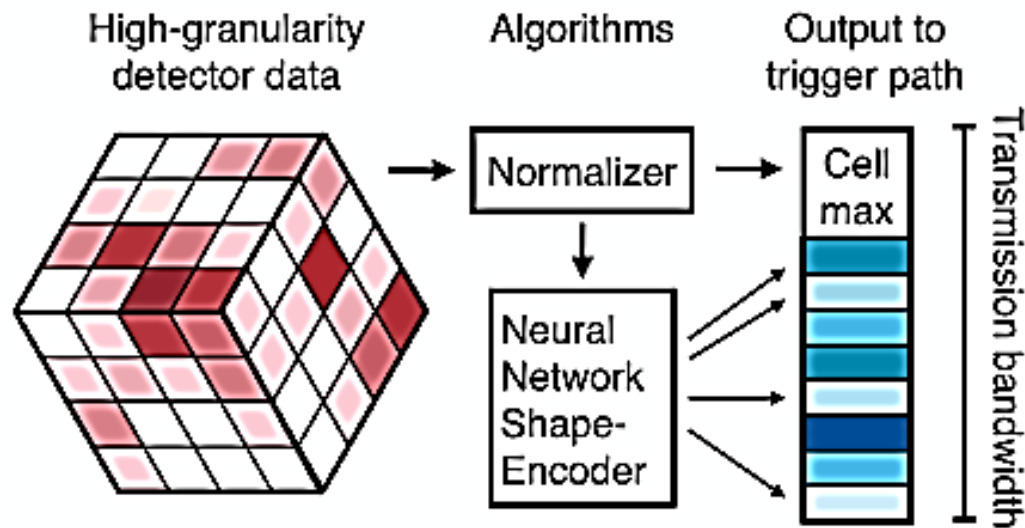
### In-Sensor Computing



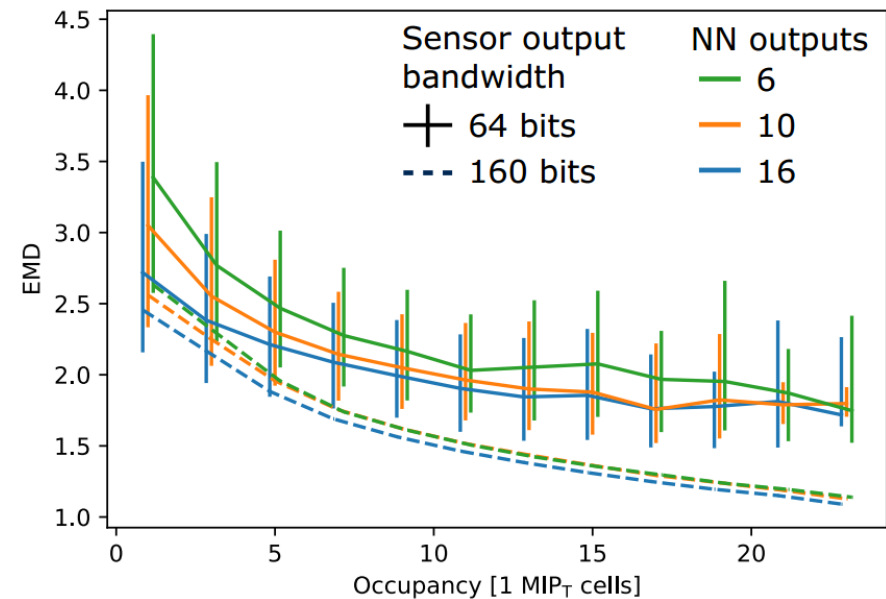
(W. Pan, Engineering, 2022)

# 3 Relative Work

- Fermilab(2021):** Front-end data compression based on convolutional neural networks for high granularity detectors
  - Two neural networks → **Encoder** and **decoder**
  - Deploying unique compression algorithms for sensors in different detector regions
  - Alleviates data transmission issues while retaining key information on detector energy distribution



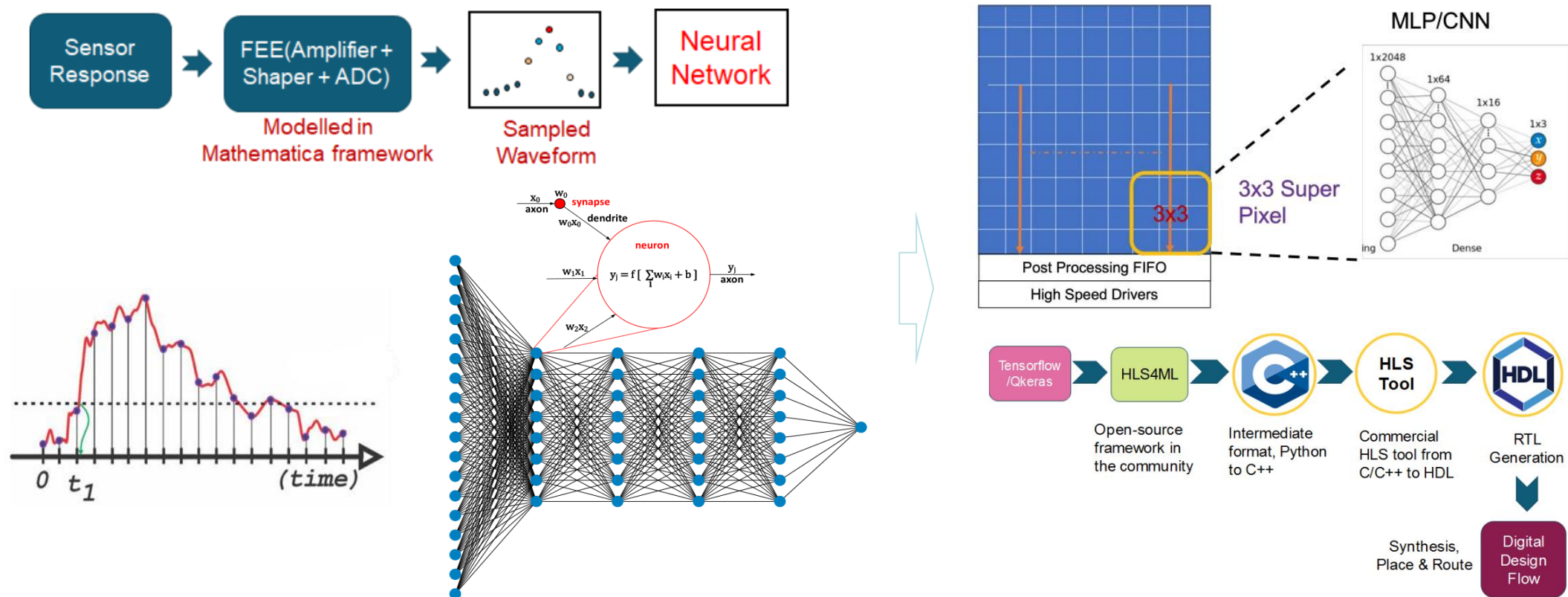
(Giuseppe Di Guglielmo, physics. Ins-det, 2021)



# 3 Relative Work

## BNL(2022): Edge computing architecture for front-end electronics of particle detectors

- Bring AI closer to the original data → **Optimize the data processing** of the increasing amount of data + **Estimating Charge Signals** from sampled Waveforms

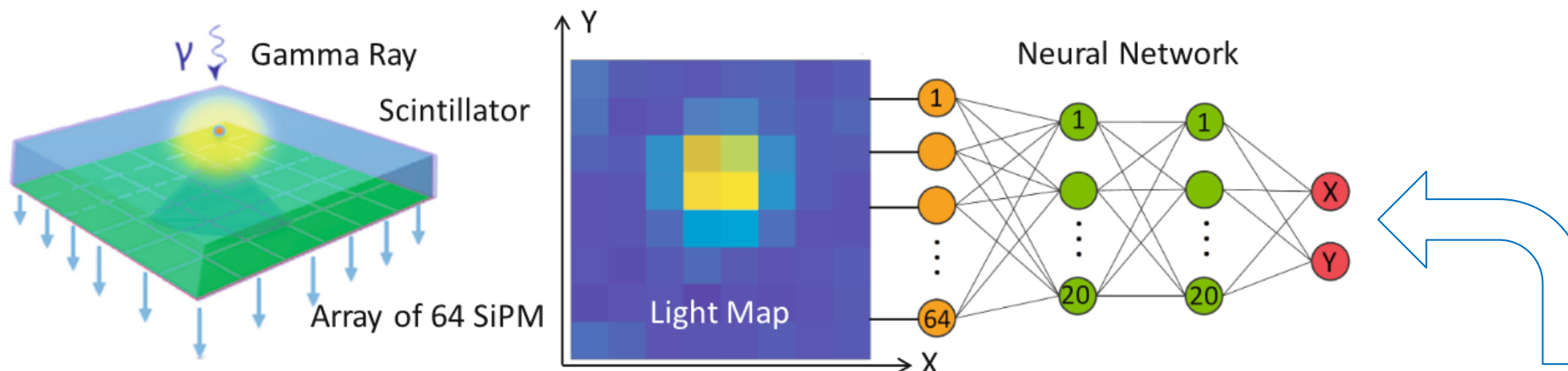


(Sandeep Miryala, BNL, ISQED, 2022)

# 3 Relative Work

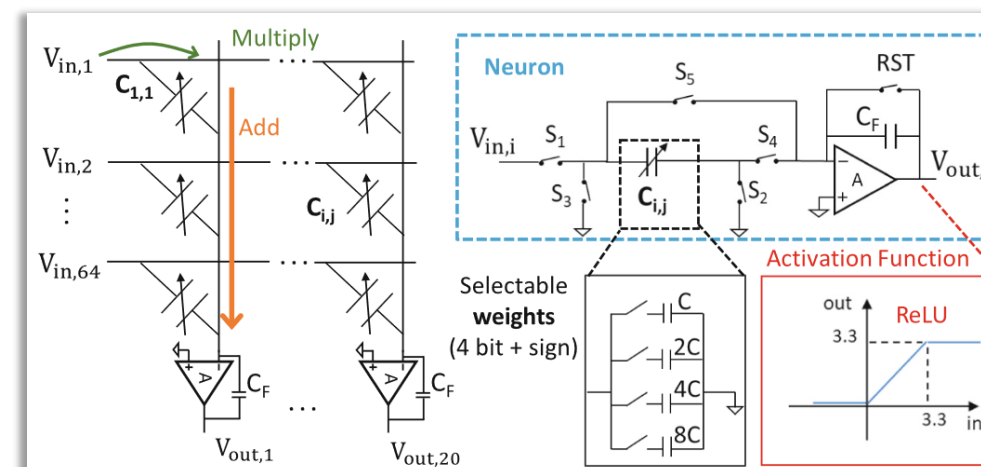
## □ INFN(2024): In-sensor Intelligence in radiation detectors

- 64 inputs, 2 hide layers, and 2 outputs → reduce the data transfer (64 → 2)



- **Locating the scintillation coordinates** of gamma ray photons in scintillators
- **Applied for medical imaging**

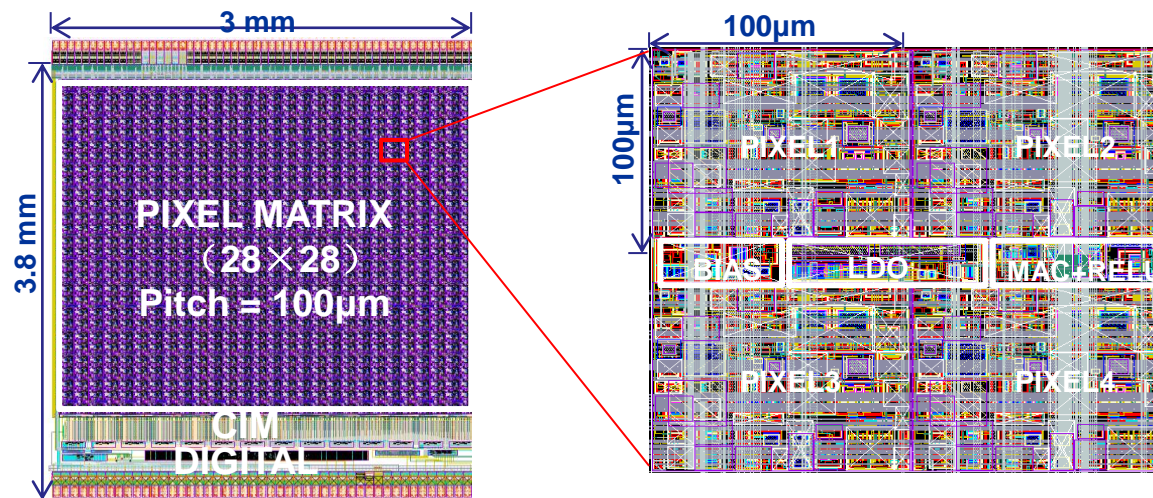
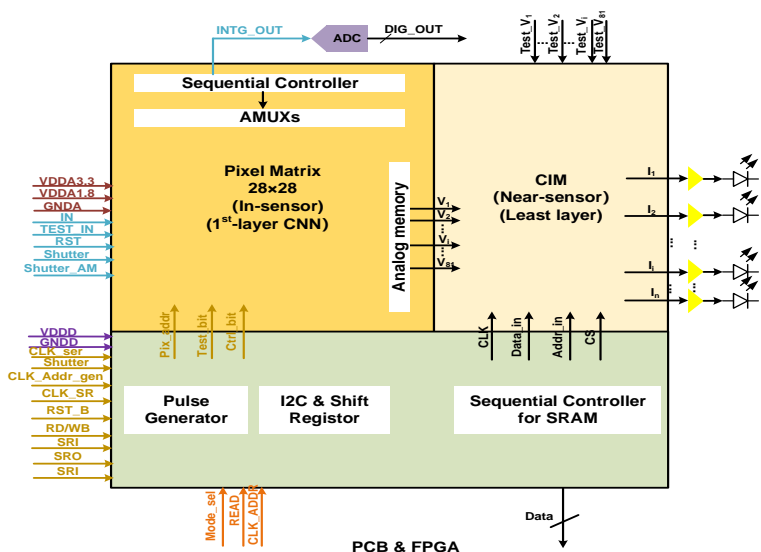
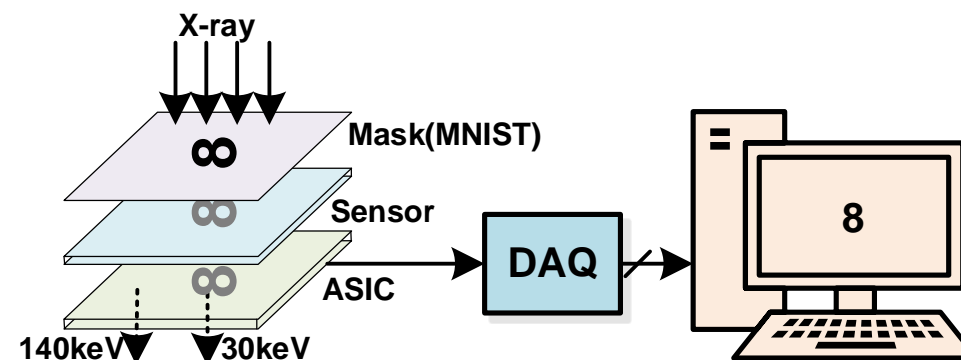
(S. D., Milano, 2024)



# 3 Alternative Proposals

## □ NPU (2023): CNN-based Front-end Processor for X-ray imaging

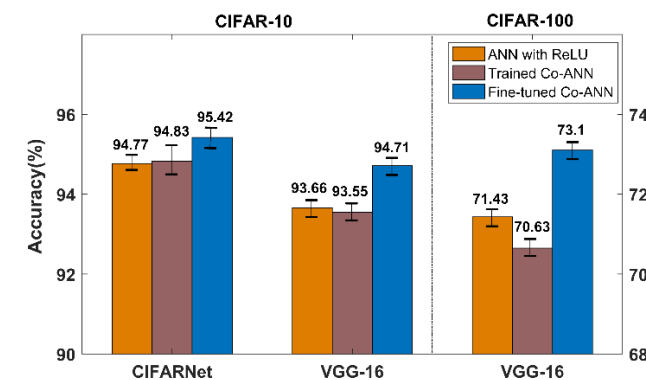
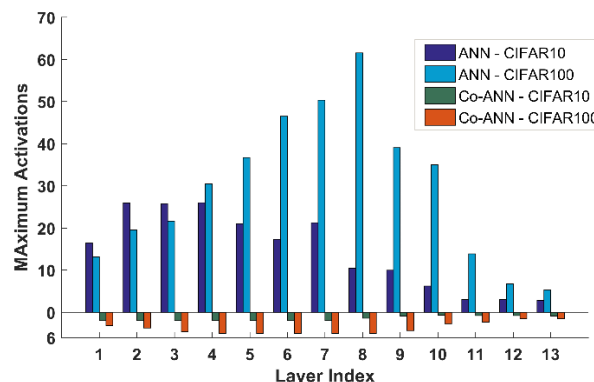
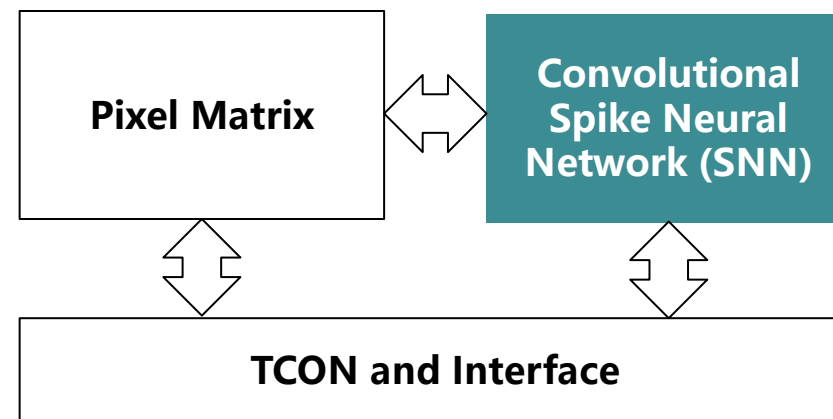
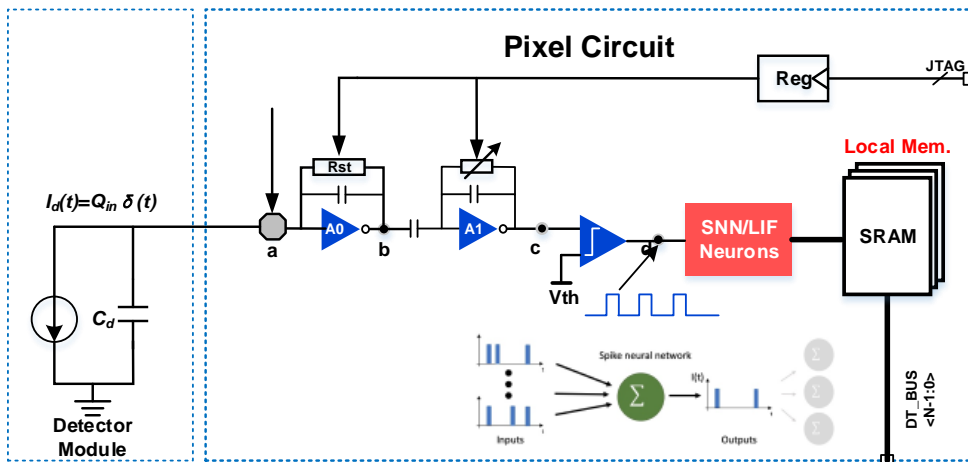
- Pixel Readout + 3 layer Neural network (784 in, 2x2 Cov. Layer, 10 out)
- Analog computing employed
- Simulated accuracy of **90 %**
- Fast X-ray Image Classification



(J. Chen, NPU, 2023)

# 3 Alternative Proposals

- **NPU (2024): SNN-based Front-end Processor for X-ray imaging**
  - Using LIF neurons to replace the integrator → improving accuracy to **95.4 %**



(D. Xu, NPU, 2024)



# **R&D of ASICs by Our Group**

# 4 ASIC Overview

## □ Developed Chips in the last 10 years

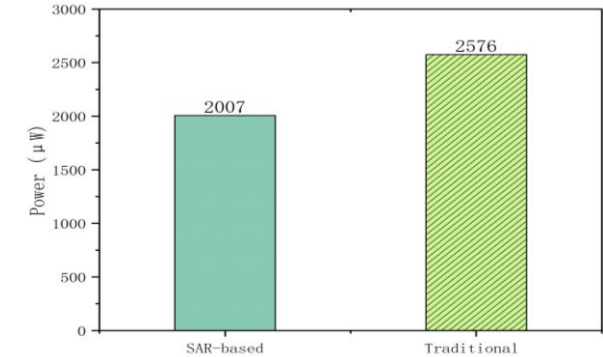
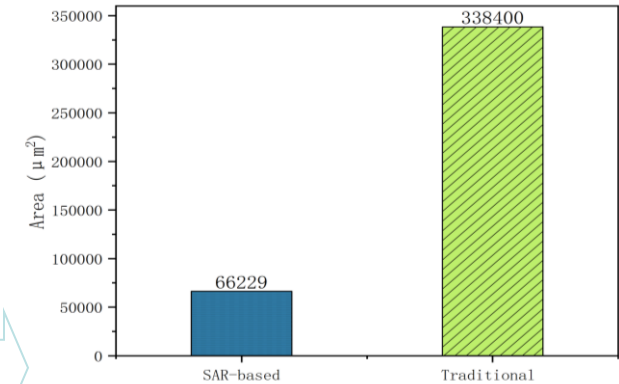
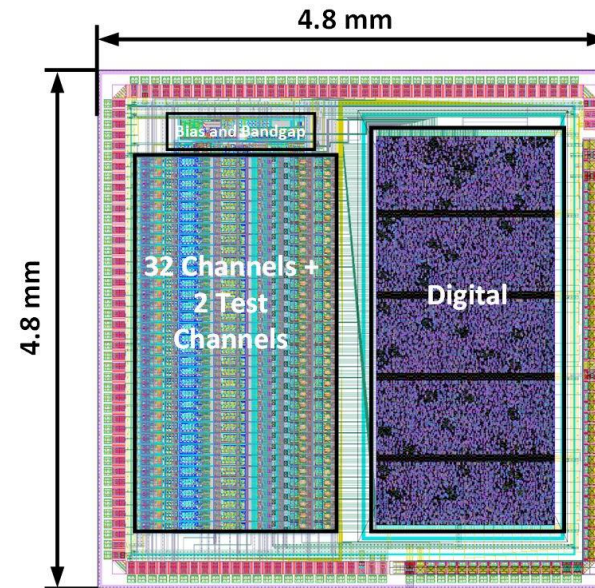
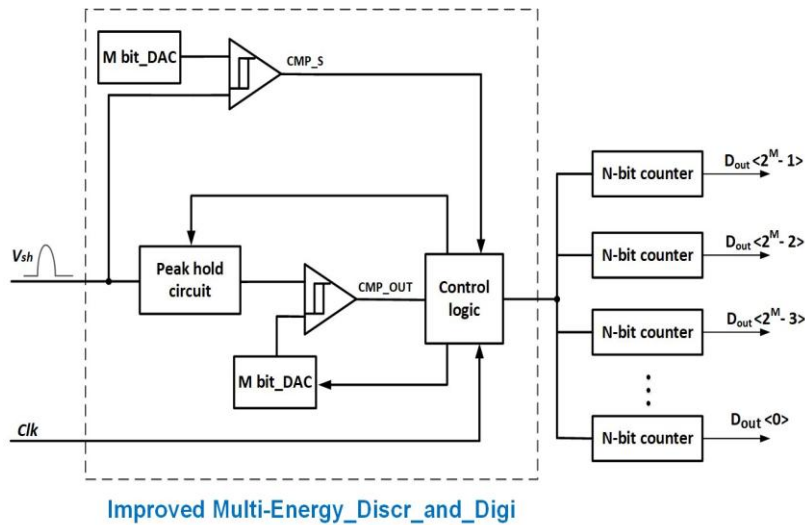
– 20+ types of ASICs and 50+ types of IP cores from 0.35  $\mu\text{m}$   $\rightarrow$  0.13  $\mu\text{m}$  CMOS



# 4 Representative work

## □ A 32-channel 8-Energy Photon-count ASIC for Si Strip Detectors

- 0.35  $\mu\text{m}$  CMOS 3.3 V, 4.8 mm  $\times$  4.8 mm, Taped out: Mar. 2024
- ENC = 53 e<sup>-</sup> + 4.2 e<sup>-</sup>/pF, **SAR-based photon count**  $\rightarrow$  X-ray diffraction imaging

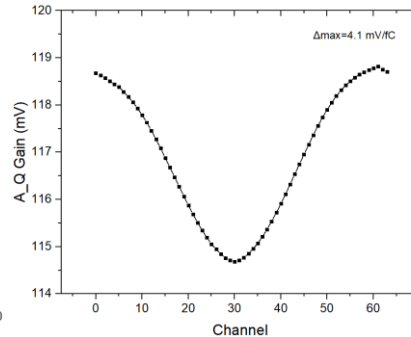
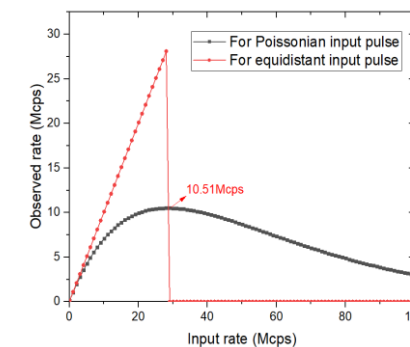
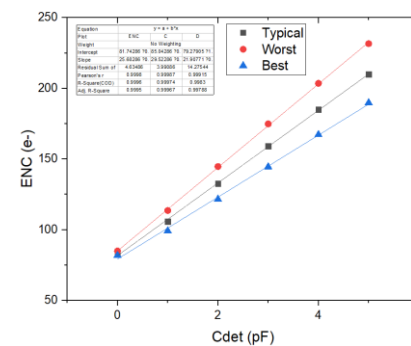
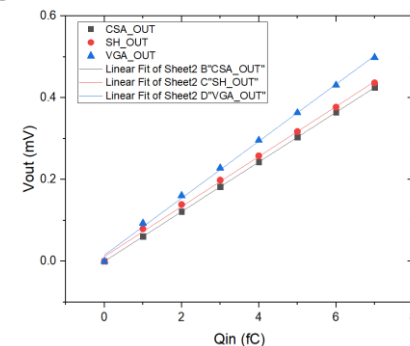
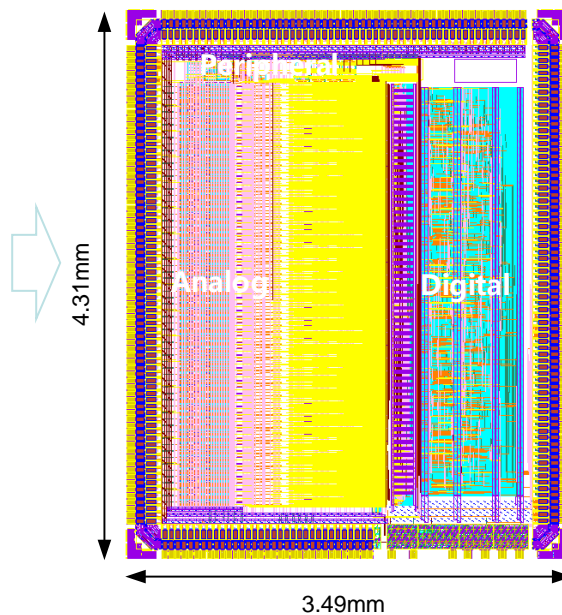
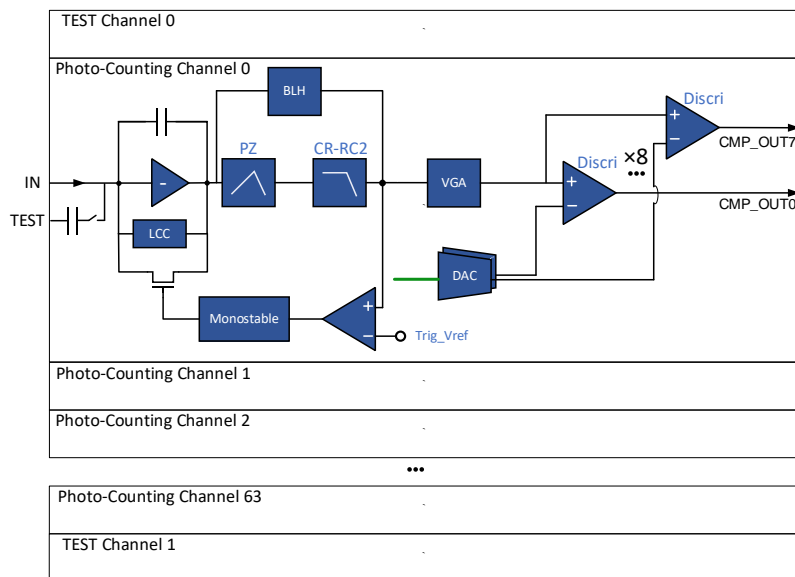


(Submitted to IEEE NSS/MIC 2024)

# 4 Representative work

## □ A 64-ch High-rate Energy-Resolving Photon Count Readout ASIC

- 0.13  $\mu\text{m}$  CMOS 1.2/3.3 V, 4.3 mm  $\times$  3.0 mm, Taped out: Mar. 2024
- Eight 5-ns Discriminators/16-bit counters in each channel
- Automatic feedback reset  $\rightarrow$  **10.5 Mcps**
- Segmented Si Strip Detectors  $\rightarrow$  CT imaging Scanners

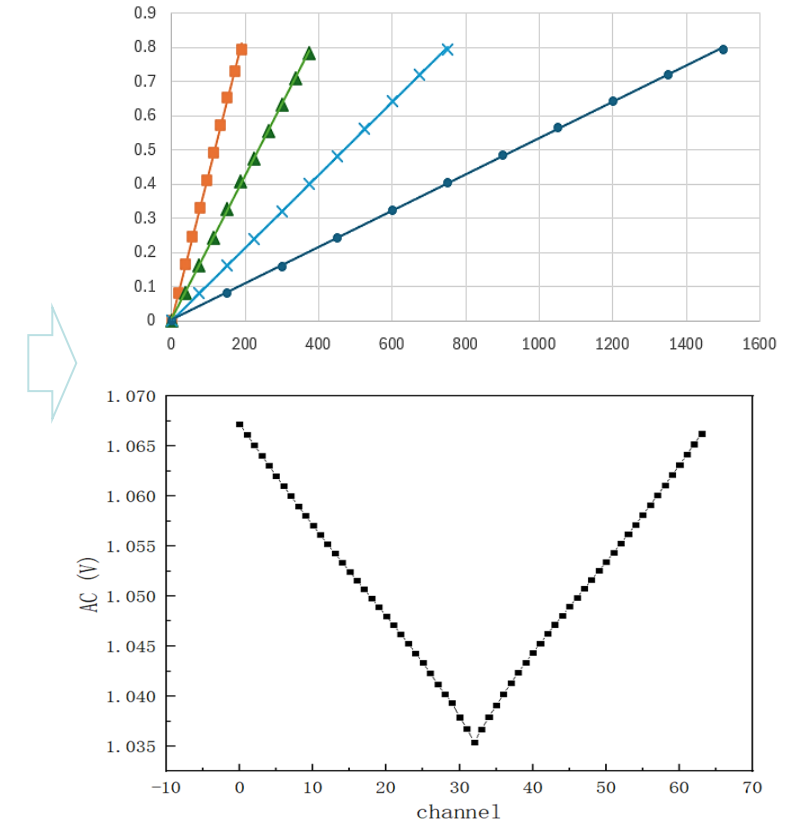
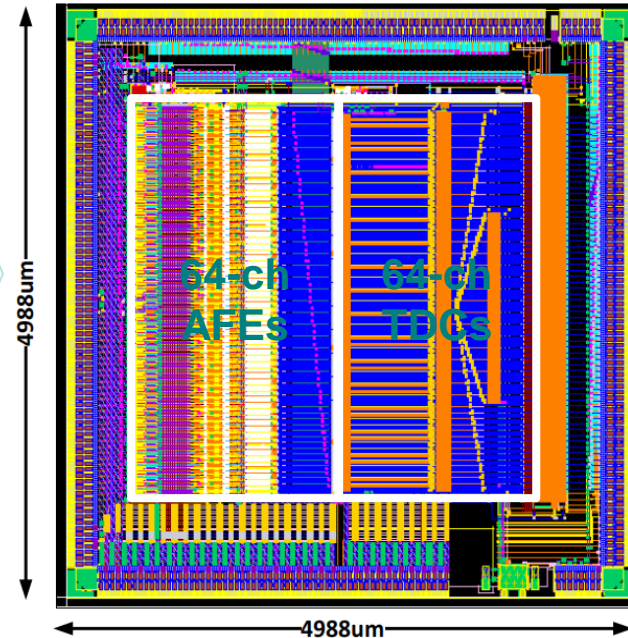
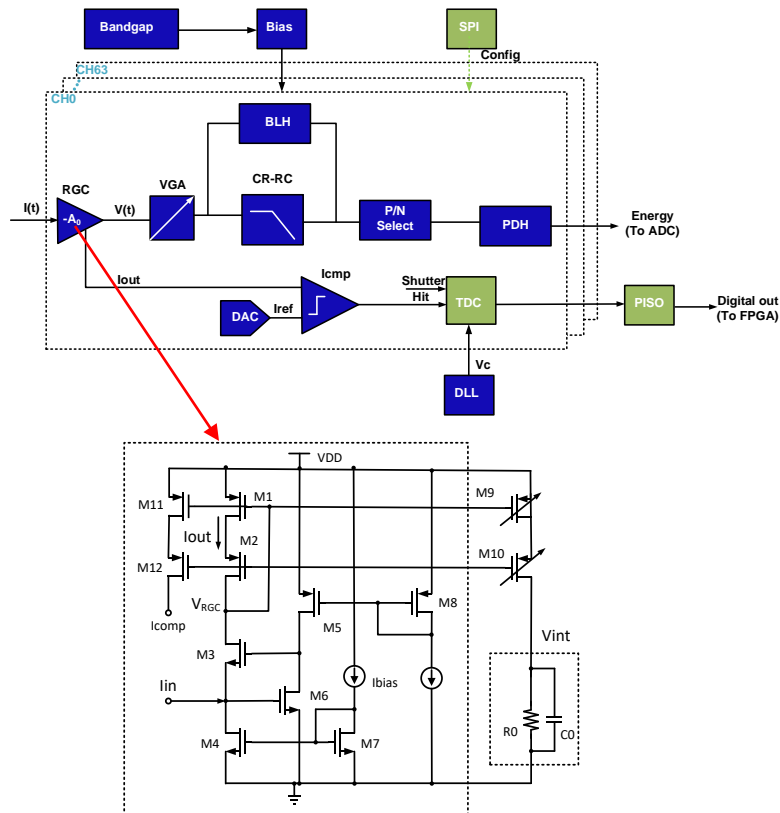


(Submitted to IEEE NSS/MIC 2024)

# 4 Representative work

## □ A 64-channel Readout ASIC with TDC for SiPM Detectors

- 0.13  $\mu\text{m}$  CMOS 1.2/3.3 V, 4.98 mm  $\times$  4.98 mm, Taped out: Mar. 2024
- $Q_{in} > 1500 \text{ pC}$ , 1 Mcps,  $T_{bin} = 312.5 \text{ ps}$   $\rightarrow$  SiPM based  $\gamma$ -ray imaging

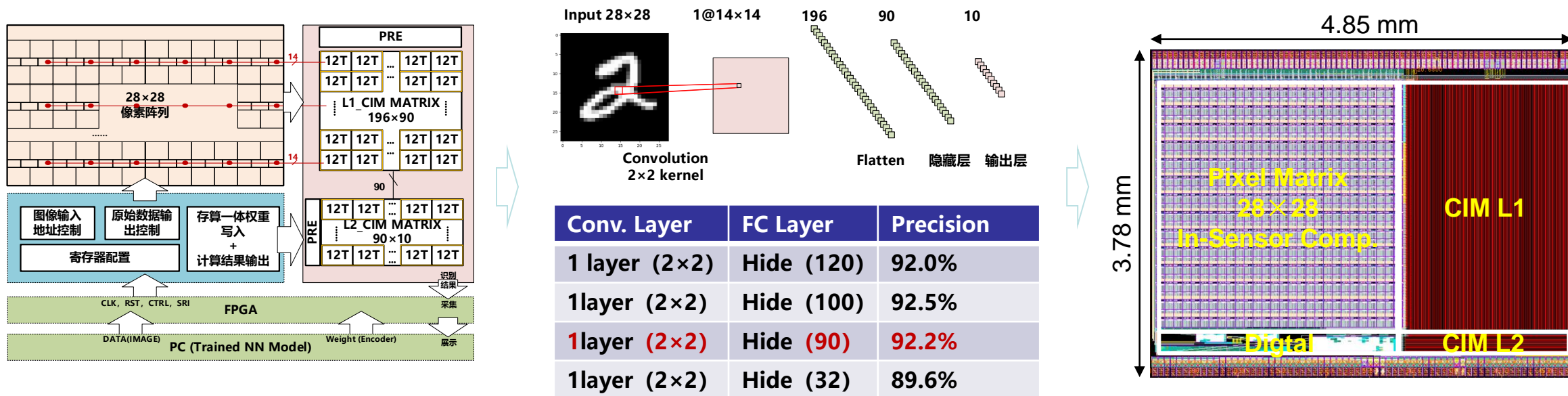


(Submitted to IEEE NSS/MIC 2024)

# 4 Representative work

## □ A front-end processor chip based on convolutional neural network

- 0.18  $\mu\text{m}$  CMOS 1.8/3.3 V, 3.78 mm  $\times$  4.85 mm, Taped out: Jun. 2024
- 28 $\times$ 28 pixel readout circuits with 2 $\times$ 2 super pixel built-in LDO
- CNN network  $\rightarrow$  1<sup>st</sup> layer (Analog MAC + ReLu) in pixel matrix + 2 layer FC (CIM)
- Precision up to **92 %** when hide layer nodes is 90



(To be submitted to TCAS-I)

# Conclusion and Perspective

# 5 Conclusion and Perspective

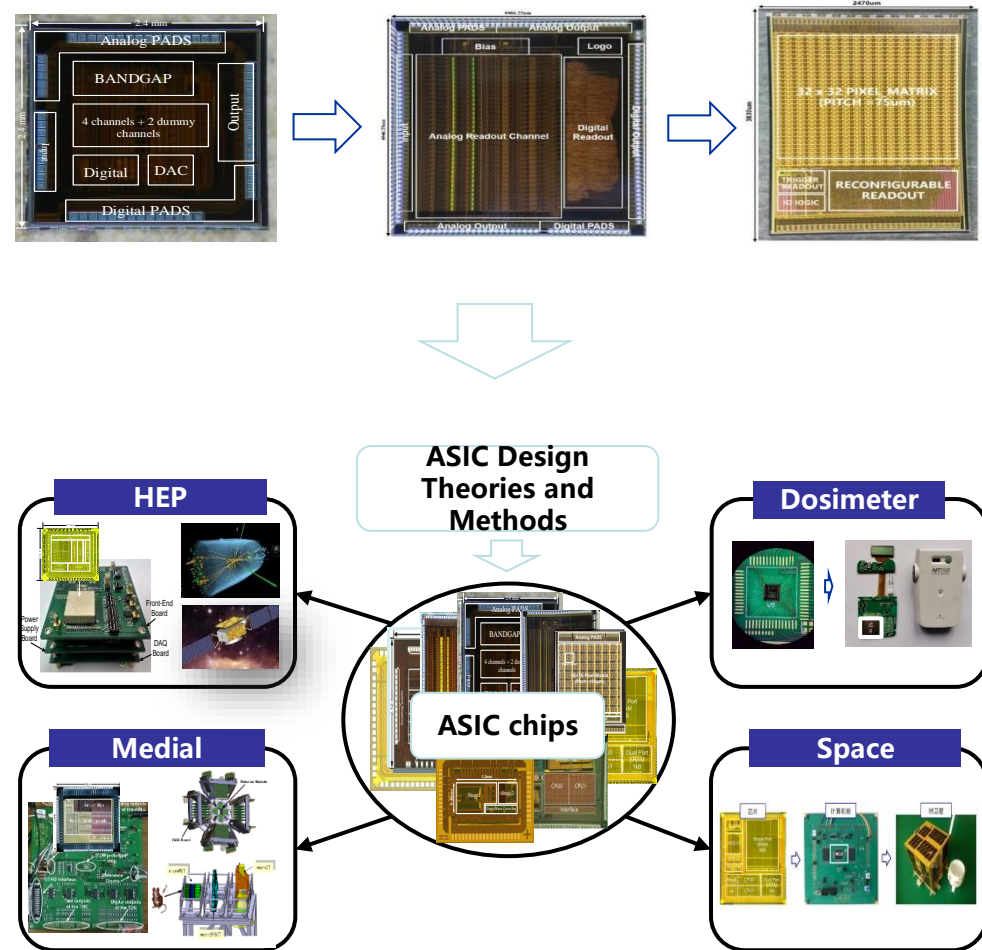
## □ Conclusion

- ✓ Basis of front-end electronics
- ✓ State-of-the-art work and Trends
- ✓ Intelligent front-end Processors
- ✓ R&D of front-end ASICs in NPU

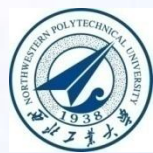
## □ Future Work

- 192-ch 8-Energy Photon-Count ASIC
- 256 × 256 pixel readout ASIC
- CNN/SNN-based front-end Processors

**More collaboration !**







**Thanks for your attention!**  
**Q & A**

